Verification of Compliance

Product Name

: Notebook Computer

Brand Name

acer

Model Number

: N19C1, EH5L1, A315-54K, A315-54KG, EH5LW, A315-54,

A315-54G, EH5LP, A315-42, A315-42G, FH5T1, EX215-51K,

EX215-51KG, FH5TW, EX215-51, EX215-51G, A315-56,

FH5LI, EX215-52, GH5TI

Applicant

: Acer Incorporated

Address

: 8F., No.88, Sec. 1, Xintai 5th Rd., Xizhi, New Taipei City 22181,

Taiwan (R.O.C)

Report Number

: S2O-A170-1903-297

Issue Date

: May 25, 2020

Applicable Standards: ETSI EN 301 489-1 V2.1.1 ETSI EN 301 489-17 V3.1.1

EN 55032:2015+AC:2016-07 Class B ITE

EN 61000-3-2:2014 EN 61000-3-3:2013

EN 61000-4-2:2009

EN 61000-4-3:2006+A1:2008+A2:2010

EN 61000-4-4:2012 EN 61000-4-5:2014 EN 61000-4-6:2014 EN 61000-4-11:2004

EN 55024:2010+A1:2015

AS/NZS CISPR32:2015 Class B ITE

Based on European Council EMC Directive 2014/30/EU, Radio equipment Directive 2014/53/EU and the specifications of the customer, one sample of the designated product has been tested in our laboratory and found to be in compliance with the EMC standards cited above.



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(Tsun-Yu Shih/ General Manager)

Date: May 25, 2020

TAF 0905

ISED CAB Code TW0905

FCC CAB Code TW1104, TW0019

VCCI Accep. No. R-11527, C-11609, T-11441, G-10010, C-20010

LAP Lab Code 200575-0

T-20009, G-10614

CE EMC Test Report

for

Notebook Computer

Trade Name : acer

Model No. : N19C1, EH5L1, A315-54K, A315-54KG,

EH5LW, A315-54, A315-54G,

EH5LP, A315-42, A315-42G, FH5T1, EX215-51K, EX215-51KG, FH5TW, EX215-51, EX215-51G, A315-56,

Report No.: S2O-A170-1903-297

FH5LI, EX215-52, GH5TI

Report Number : S2O-A170-1903-297

Date of Receipt : October 22, 2019

Date of Report : May 25, 2020

Prepared for

Acer Incorporated

8F., No.88, Sec. 1, Xintai 5th Rd., Xizhi, New Taipei City 22181, Taiwan (R.O.C)



Prepared by

Central Research Technology Co.

11, Lane 41, Fushuen St., Jungshan Chiu, Taipei 104, Taiwan

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Verification of Compliance

Equipment Under Test : Notebook Computer

Model No. : N19C1, EH5L1, A315-54K, A315-54KG, EH5LW, A315-54,

A315-54G, EH5LP, A315-42, A315-42G, FH5T1, EX215-51K, EX215-51KG, FH5TW, EX215-51, EX215-51G, A315-56,

Report No.: S2O-A170-1903-297

FH5LI, EX215-52, GH5TI

Applicant: Acer Incorporated

Address : 8F., No.88, Sec. 1, Xintai 5th Rd., Xizhi, New Taipei City

22181, Taiwan (R.O.C)

Applicable Standards : ETSI EN 301 489-1 V2.1.1

ETSI EN 301 489-17 V3.1.1

EN 55032:2015+AC:2016-07 Class B ITE

EN 61000-3-2:2014 EN 61000-3-3:2013 EN 61000-4-2:2009

EN 61000-4-3:2006+A1:2008+A2:2010

EN 61000-4-4:2012 EN 61000-4-5:2014 EN 61000-4-6:2014 EN 61000-4-11:2004

EN 55024:2010+A1:2015

AS/NZS CISPR32:2015 Class B ITE

Date of Testing : November 6~11, 2019

Deviation: The method, configuration and arrangement of the tests are

following the requirement of customer and the applicable

standards cited above.

Condition of Test Sample: Engineering Sample

We, **Central Research Technology Co**., hereby certify that one sample of the designated product was tested in our facility during the period mentioned above. The test records, data evaluation and Equipment Under Test (EUT) configurations shown in the present report are true and accurate representation of the measurements of the sample's EMC characteristics under the conditions herein specified.

The test results show that the EUT as described in the present report is in compliance with the requirements set forth in the standards mentioned above and apply to the tested sample identified in the present report only. The test report shall not be reproduced, except in its entirety, without the written approval of Central Research Technology Co.

PREPARED BY

Rosa High

___ , DATE :

May 15, 2000

 Γ

(Rosa Hsieh/System Executive)

APPROVED BY

DATE

May 21, 2020

(Tsun-Yu Shih/General Manager)

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1. General Description

This report is a copy version for adding model numbers: FH5LI, EX215-52, GH5TI due to the requirements of marketing. All the test data are copies from the report: S1O-A170-1903-297 of Central Research Technology Co.

1.1 General Description of EUT

Equipment Under Test : Notebook Computer

Model No. : N19C1, EH5L1, A315-54K, A315-54KG, EH5LW,

A315-54, A315-54G, EH5LP, A315-42, A315-42G,

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FH5T1, EX215-51K, EX215-51KG, FH5TW,

EX215-51, EX215-51G, A315-56, FH5LI, EX215-52,

GH5TI

Power in : Supplied by the power adapter listed on page 8

Highest Operating Frequency: 2.6GHz from the test specification

Manufacturer : Acer Incorporated

Function Description

The EUT is an engineering sample of the Notebook Computer. Please refer to the user's manual for the details.

The products of all the models are identical, they are for different market only.

The I/O ports of EUT for final verification test are listed below:

No.	I/O Port Type	Quantity
1	USB 2.0 port	2
2	USB 3.0 port	1
3	HDMI port	1
4	Audio output/ Mic. combo port	1
5	LAN port	1

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The devices (supplied by manufacturer) can be installed inside the EUT are listed below:

Components	Vendor	Description			
		LA-H80			
		LA-H781			
MDDaad		LA-H782			
MB Board	compal	LA-H791			
		LA-H792			
		LA-J801			
	A.A.D.	Product Description of Processor Manufacturer an Max			
	AMD	Speed Up to and include 2.6GHz			
CPU		Product Description of Processor Manufacturer an Max			
	Intel	Speed Up to and include 2.3GHz			
	_	N156HGA (FHD)			
	INNOLUX	N156BGA (HD)			
		B156HTN06 (FHD)			
LCD	AUO	B156XTN08 (HD)			
	ВОЕ	NT156FHM (FHD)			
		NT156WHM (HD)			
	GI.:	CNFHH6221004970LH			
	Chicony	CNFG02321004970LH			
Camera	Liteon	6SF009N2			
	TECH EDON'T	1YHJZZZ000S			
	TECH-FRONT	1YHJZZZ000P			
MEMODY		Modules:DDR4 2666			
MEMORY	Modules:DDR4 3200				
ON BOARD MEMORY		Modules:DDR4 2666			
PCIE SSD		Max up to 1 pcs			
SATA HDD		Max up to 1 pcs			
	AUDATA	AP16M4J			
	MURATA	AP18C4K			
Battery	PANASONIC	AP16M5J			
	1.66	AP18C8K			
	LGC	AC14B18J			
WLAN+BT Combo	Intel	3168 NGW			
(optional)	LITE-ON	NFA435A			

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Final Verification Mode from test specification

	Test Mode	Test Model Test No. Voltage		Test Item		
	External Monitor		230V/50Hz	 Conducted Emission Test(LISN&ISN) EN 61000-3-2, EN 61000-3-3 and all EMS tests shown in clause 1.3 (excluding Dip Test) 		
1	HDMI 3840*2160@60Hz + EUT panel	A315-56	120V/60Hz	Conducted Emission Test (LISN)		
	1920*1080@60Hz		110V/60Hz	Radiated Emission Test (30MHz~1GHz & above 1GHz)		
			240V/50Hz	Dip Test		
			100V/50Hz	י טוף ופאנ		

Report No.: S2O-A170-1903-297

All the devices listed below are chosen by the applicant to be the representative configuration for testing in this report.

Device	Specification		
MB	Compal / LA-J801		
CPU	Intal / iE 102EC1.1C		
(1526 Pin)	Intel / i5-1035G1 1G		
LCD	AUO / B156HTN06 (FHD)		
Camera	TECH-FRONT/ 1YHJZZZ000P		
on board Memory	DDR4 2666 4GB		
MEMORY	DDR4 2666 4GB		
SSD	KINGSTON / RBU-SNS8154P3 256G		
HDD	TOSHIBA DIGI / MQ04ABF100 1TB		
BATTERY	LGC / AP18C8K		
WLAN+BT	Qualcomm Atheros / QCNFA435		
ADAPTER	LITE-ON / PA-1450-26		

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1.3 Applied standards

Based on European Council EMC Directive 2014/30/EU, Radio equipment Directive 2014/53/EU and the specifications of the manufacturer, the applied standards to evaluate the compliance of the EUT are as following:

Report No.: S2O-A170-1903-297

Арр	olied Standards	Test Items	Results
	☑ EN 55032:2015+AC:2016-07	Conducted Emission Measurement	<u>PASS</u>
	Class B ITE	Radiated Emission Measurement	<u>PASS</u>
	☑ EN 61000-3-2:2014	Harmonic Current Emission Measurement	<u>PASS</u>
☑	☑ EN 61000-3-3:2013	Voltage Fluctuation and Flicker Emission Measurement	<u>PASS</u>
ETSI EN 301 489-1	☑ EN 61000-4-2:2009	Electrostatic discharge Test (ESD)	<u>PASS</u>
V2.1.1 ETSI EN 301 489-17	☑ EN 61000-4-3: 2006+A1:2008+A:2010	Radiated electromagnetic field immunity Test (RS)	<u>PASS</u>
V3.1.1	☑ EN 61000-4-4:2012	Electrical fast transient / burst immunity Test (EFT)	<u>PASS</u>
	☑ EN 61000-4-5:2014	Surge immunity Test	<u>PASS</u>
	☑ EN 61000-4-6:2014	Immunity to conducted disturbances, induced by radio-frequency fields (CS)	<u>PASS</u>
	☑ EN 61000-4-11:2004	Voltage dips, short interruptions Test	<u>PASS</u>
	☑ EN 61000-4-2:2009	Electrostatic discharge Test (ESD)	<u>PASS</u>
	☑ EN 61000-4-3: 2006+A1:2008+A2:2010	Radiated electromagnetic field immunity Test (RS)	<u>PASS</u>
	☑ EN 61000-4-4:2012	Electrical fast transient / burst immunity Test (EFT)	<u>PASS</u>
☑ EN 55024:2010+	☑ EN 61000-4-5:2014	Surge immunity Test	<u>PASS</u>
A1:2015	☑ EN 61000-4-6:2014	Immunity to conducted disturbances, induced by radio-frequency fields (CS)	<u>PASS</u>
	□ EN 61000-4-8:2010	Power frequency magnetic field immunity Test (PFM)	<u>N/A</u> *
	☑ EN 61000-4-11:2004	Voltage dips, short interruptions Test	<u>PASS</u>
☑ AS/NZS CISPR32:2	2015 Class B ITF	Conducted Emission Measurement	<u>PASS</u>
E AO/NZO OIOI NOZ.Z		Radiated Emission Measurement	<u>PASS</u>

Remark: *: The manufacturer determines from the electrical characteristic and intended usage of the EUT that one or more measurements (tests) are unnecessary.

According to applied standards, the measurement instrumentation uncertainty is not taken into account in the determination of compliance.

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1.4 Description of Performance Criteria

Product Standard: EN 55024

Criteria A: normal performance within levels specified by the manufacturer,

requestor or purchaser;

Criteria B: temporary loss of function or degradation of performance which ceases

after the disturbance ceases, and from which the EUT recovers its

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normal performance, without operator intervention;

Criteria C: temporary loss of function or degradation of performance, the correction

of which requires operator intervention;

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Product Standard : ETSI EN 301 489-17

Criteria	During test	After test		
A	Shall operate as intended. (see note 1). Shall be no loss of function. Shall be no unintentional transmissions.	Shall operate as intended. Shall be no degradation of performance (see note 3). Shall be no loss of function. Shall be no loss of stored data or user programmable functions		
В	May show loss of function (one or more). May show degradation of performance (see note 2). Shall be no unintentional transmissions.	Functions shall be self-recoverable. Shall operate as intended after recovering. Shall be no degradation of performance (see note 3). Shall be no loss of stored data or user programmable functions		
С	May be loss of function (one or more)	Functions shall be recoverable by the operator. Shall operate as intended after recovering. Shall be no degradation of performance (see note 3).		

- NOTE 1:Operate as intended during the test allows a level of degradation not below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance. If the minimum performance level or the permissible performance degradation is not specified by the manufacturer then either of these may be derived from the product description and documentation(including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended.
- NOTE 2: Degradation of performance during the test is understood as a degradation to a level not below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance. If the minimum performance level or the permissible performance degradation is not specified by the manufacturer then either of these may be derived from the product description and documentation(including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended.
- NOTE 3: No degradation of performance after the test is understood as no degradation below a minimum performance level specified by the manufacturer for the use of the apparatus as intended. In some cases the specified minimum performance level may be replaced by a permissible degradation of performance. After the test no change of actual operating data or user retrievable data is allowed. If the minimum performance level or the permissible performance degradation is not specified by the
 - manufacturer then either of these may be derived from the product description and documentation (including leaflets and advertising) and what the user may reasonably expect from the apparatus if used as intended.

Performance criteria for Continuous phenomena applied to Transmitters (CT)

The performance criteria A shall apply. Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an ACKnowledgement (ACK) or not-acknowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

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Performance criteria for Transient phenomena applied to Transmitters (TT)

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration, for which performance criteria C shall apply. Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an acknowledgement (ACK) or not-acknowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

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Performance criteria for Continuous phenomena applied to Receivers (CR)

The performance criteria A shall apply. Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

Performance criteria for Transient phenomena applied to Receivers (TR)

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration for which performance criteria C shall apply. Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

Pass/Fail verdict:

During the link test, the Wifi link shall have been maintained and the windows of monitor PC may not deviate from those before the test.

Monitoring:

The status of connection has been monitored from the display of the monitor PC via a camera or witness.

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The EUT is an unique unit connected with other necessary accessories and support units listed in the next section. It has been tested against each standard after the following setup steps:

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- a. Connect the EUT and all the support units to the appropriate power source.
- b. Turn on the EUT and all the accessories and support units.
- c. The EUT load an EMC test software (BurnIn Test V8.1) and execute it under the Windows environment.
- d. The EUT runs ITU color bar on the display device(s) continuously.(for EN 55032 tests)
- e. The EUT runs "H" pattern on the display device(s) continuously. (for other tests)
- f. The EUT sends audio signal to the audio device(s).
- g. The EUT sends the CCD receiving image to the display device(s) continuously.
- h. The EUT reads/ writes messages from/ to the internal & external storage device(s) continuously.
- Let the Wireless functions of EUT operating continuously.
- j. Another PC sends/receives messages to/from the EUT through Wireless AP Router by executing the command of "PING".
- k. For Wifi function [EN 301 489-17]
 - k-1. Via wireless access point, EUT transmits/receives messages to/from another PC.
 - k-2. Monitor the status of connection by seeing the window of another PC.
- Repeat and keep the setup steps listed above before and during all tests.

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1.6 The Support Units

Conducted Emission Test

No.	Unit	Model No./ Serial No.	FCC ID	Trade Name	Power Cord	Supported by lab.	Note
1	LCD Monitor	U2718Q/ 1JD0FJ2	DoC	DELL	1.8m	✓	
2	Earphone & Microphone	ZBW4308GL/ 20160904	DoC	xiaomi.tw	N/A	✓	
3	USB Mouse	SM-9625/ 12702544	DoC	ACER	N/A	✓	
4	USB 3.0 HDD	SRD00F1/ NA9EN6MD	DoC	Seagate	N/A	✓	
5	USB 2.0 HDD	320G FreeAgent Go/ 2GE6K3PZ	DoC	Seagate	N/A	✓	

Radiated Emission Test

No.	Unit	Model No./	FCC ID	Trade	Power	Supported	Note	
		Serial No.		Name	Cord	by lab.		
1	LCD Monitor	P2715Q/	DoC	DELL	1.8m	✓		
'	LCD MONITOR	9W3RBC2	DOC	DLLL	1.0111	•		
2	Earphone &	ZBW4354TY/	DoC	xiaomi.tw	N/A	✓		
_	Microphone	20170203	DOC	DOC XIA	AlaOIIII.tw	IN//A	•	
_	1100 0 0 1100	Canvio Basics/	D - 0	TOCLUDA	N/A	✓		
3	USB 3.0 HDD	88GSSF27SHJG	DoC	TOSHIBA	IN/A			

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ESD Test

No.	Unit	Model No./ Serial No.	FCC ID	Trade Name	Power Cord	Supported by lab.	Note
1	LCD Monitor	U2718Q/ CN-0M5R5f-QDC00- 7BT-0HWL-A02	DoC	DELL	1.8m	*	
2	Earphone & Microphone	ZBW4354TY/ 20170208	DoC	xiaomi.tw	N/A	✓	
3	USB Mouse	MS111-P/ CN-011D3V-71581-091- 3BS9	DoC	DELL	N/A	√	
4	USB 3.0 HDD	HD-LB2.0TU3-A2/ 55292030316682	DoC	BUFFALO	1.2m	✓	
5	USB 2.0 HDD	F12-UF/ A0100223-36h0001	DoC	TeraSys	N/A	√	

RS and CS Tests

No.	Unit	Model No./ Serial No.	FCC ID	Trade Name	Power Cord	Supported by lab.	Note
1	LCD Monitor	P2715Q/ CN-0NTMTN-74445- 6CA-ABVL	DoC	DELL	1.8m	*	
2	Earphone & Microphone	ZBW4354TY/ 20170209	DoC	KTNET	N/A	✓	
3	USB Mouse	MS111-L/ CN-09RRC7-48729- 37C-255X	DoC	DELL	N/A	√	
4	USB 3.0 HDD	HD-PCTU3/ 85295534404863	DoC	BUFFALO	N/A	~	
5	USB 2.0 HDD	F12/ A0100206-2740015	DoC	TeraSys	N/A	✓	

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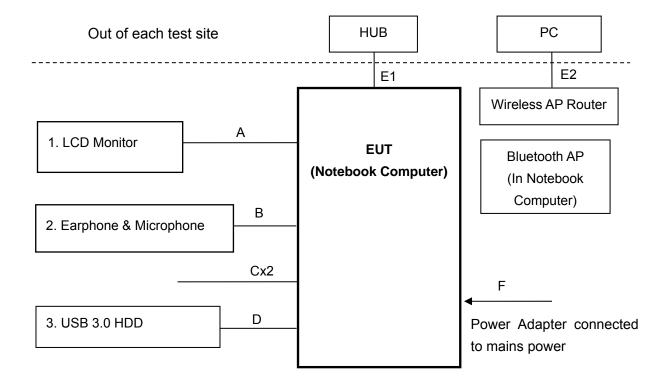
Other Tests

No.	Unit	Model No./ Serial No.	FCC ID	Trade Name	Power Cord	Supported by lab.	Note
1	LCD Monitor	P2715Q/ CN-0NTMTN-74445- 6CA-ABVL	DoC	DELL	1.8m	√	
2	Earphone & Microphone	ZBW4308GL/ 20160908	DoC	xiaomi.tw	N/A	✓	
3	USB Mouse	MS111-P/ CN-093H7Y-71581-3A9- 0DFW	DoC	DELL	N/A	√	
4	USB 3.0 HDD	HD-PCTU3/ 85295534404825	DoC	BUFFALO	N/A	✓	
5	USB 2.0 HDD	320G FreeAgent Go/ 2GE4N4X3	DoC	Seagate	N/A	✓	

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1.7 Layout of the Setup

Radiated Emission Test



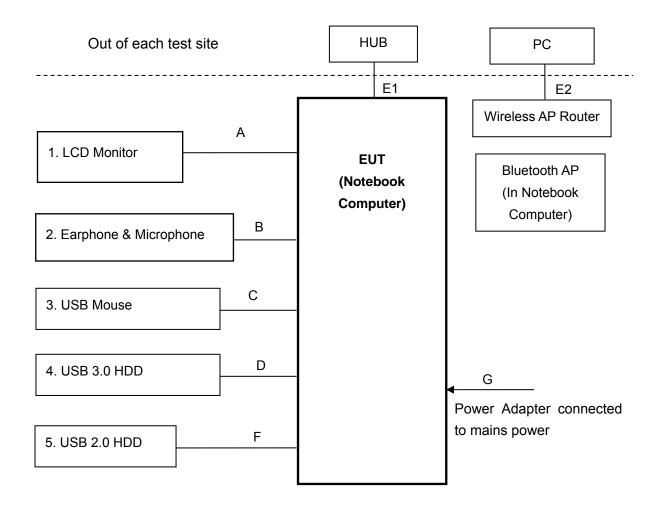
No.	Cable	Path	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
Α	HDMI Cable	Monitor to EUT HDMI port.	1.5m	~			√	Model Name: RP- CDHS1 5-K
В	Earphone & Microphone Cable	Earphone & Microphone to EUT Audio/ Mic. port	1.2m	✓			✓	
С	USB 2.0 A to B cable	USB 2.0 A to B cable to EUT USB 2.0 port	1.8m	~			1	Floating, Model Name: H-USB- ABPP01
D	USB 3.0 A to Micro USB cable	USB 3.0 HDD to EUT USB 3.0 port	1.0m	~			√	Model Name: JS-41- 14021
E1	LANGSHI	Server (HUB) to EUT LAN port.	1.5m				✓	Cat.5e
E2	LAN Cable	Wireless AP Router to PC LAN port.	1.5m				✓	Cat.5e
F	Power cable	Power Adapter to EUT DC port	1.5m					

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Other Tests



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Connecting Cables:

For ESD Test

No.	Cable	Path	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
Α	HDMI Cable	Monitor to EUT HDMI port.	1.8m	~			√	Model Name: JS41- 14050
В	Earphone & Microphone Cable	Earphone & Microphone to EUT Audio/ Mic. port	1.2m	~			✓	
С	USB Mouse Cable	USB Mouse to EUT USB 2.0 port	1.8m	✓			✓	
D	USB 3.0 A to B cable	USB 3.0 HDD to EUT USB 3.0 port	1.8m	~			√	Model Name: BUSB31 80ABM B
E1	LAN Cable	Server (HUB) to EUT LAN port.	1.5m				✓	Cat.5e
E2	Livit Gable	Wireless AP Router to PC LAN port.	1.5m				✓	Cat.5e
F	USB 2.0 A to B cable	USB 2.0 HDD to EUT USB 2.0 port	1.8m	~			√	Model Name: H-USB- ABPP01
G	Power cable	Power Adapter to EUT DC port	1.5m					

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For RS and CS Tests

No.	Cable	Path	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
Α	HDMI Cable	Monitor to EUT HDMI port.	1.8m	~			√	Model Name: JS41- 14050
В	Earphone & Microphone Cable	Earphone & Microphone to EUT Audio/ Mic. port	1.2m	✓			✓	
С	USB Mouse Cable	USB Mouse to EUT USB 2.0 port	1.8m	✓			✓	
D	USB 3.0 A to Micro USB cable	USB 3.0 HDD to EUT USB 3.0 port	1.0m	*			✓	Model Name: JS-41- 14021
E1	LAN Cable	Server (HUB) to EUT LAN port.	1.5m				✓	Cat.5e
E2	Livit Gable	Wireless AP Router to PC LAN port.	1.5m				✓	Cat.5e
F	USB 2.0 A to B cable	USB 2.0 HDD to EUT USB 2.0 port	1.8m	✓			√	Model Name: H-USB- ABPP01
G	Power cable	Power Adapter to EUT DC port	1.5m					

No.	Cable	Path	Length	Shielded	Core	Shielded Backshell	Supported by lab.	Note
Α	HDMI Cable	Monitor to EUT HDMI port.	1.8m	✓			√	Model Name: JS41- 14050
В	Earphone & Microphone Cable	Earphone & Microphone to EUT Audio/ Mic. port	1.2m	✓			✓	
С	USB Mouse Cable	USB Mouse to EUT USB 2.0 port	1.8m	✓			✓	
D	USB 3.0 A to Micro USB cable	USB 3.0 HDD to EUT USB 3.0 port	1.0m	~			*	Model Name: JS-41- 14021
E1	LAN Cable	Server (HUB) to EUT LAN port.	1.5m				✓	Cat.5e
E2	Li ii Cabio	Wireless AP Router to PC LAN port.	1.5m				✓	Cat.5e
F	USB 2.0 A to Mini USB cable	USB 2.0 HDD to EUT USB 2.0 port	1.0m	✓			√	Model Name: JS-41- 14032
G	Power cable	Power Adapter to EUT DC port	1.5m					

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1.8 Test Capability

Test Facility

The test facility used for evaluating the conformance of the EUT with each standard in the present report meets what required in CISPR16 series and IEC/EN 61000-4-3.

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Test Room	Type of Test Room	Descriptions			
TR1	10m semi-anechoic chamber	For the radiated emission measurement. (below 1GHz)			
TR1	10m semi-anechoic chamber with absorber	For the radiated emission measurement. (above 1GHz)			
TR11	3m semi-anechoic chamber	For the radiated emission measurement. (below 1GHz)			
TR5	Shielding Room				
TR20	Shielding Room	For the conducted emission measurement.			
TR3	3m fully-anechoic chamber	For the radiated immunity test.			
TR7	Shielding Room				
TR8	Shielding Room				
TR4	Shielding Room	For the Current Harmonic / Voltage Flicker			
AR	Shielding Room	and other immunity tests.			
TR12	Plane Grounding Site				
TR14	Plane Grounding Site				
TR300	3m fully-anechoic chamber	For the radiated emission measurement. (above 1GHz)			

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Central Research Technology Co. has been accredited / filed / authorized by the agencies listed in the following table.

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Certificate	Nation	Agency	Code	Mark		
	USA	NVLAP	200575-0	ISO/IEC 17025		
	USA	FCC	TW1104, TW0019	ISO/IEC 17025		
	R.O.C.	TAF	0905	ISO/IEC 17025		
	(Taiwan)	IAF	0905	130/IEC 17025		
Accreditation			SL2-IN-E-0033,			
Certificate	R.O.C. (Taiwan)		SL2-IS-E-0033,			
		BSMI	SL2-R1/R2-E-0033,	ISO/IEC 17025		
			SL2-A1-E-0033,			
			SL2-L1-E-0033			
	Canada	IC	TW0905	ISO/IEC 17025		
Sito Filing			R-11527,C-11609,T-11441,	Toot facility list 9		
Site Filing Document	Japan	VCCI	G-10010,C-20010, G-10614,	Test facility list & NSA Data		
Document			T-20009	NSA Dala		
Authorization Certificate	Germany	TUV	UA 50235497	ISO/IEC 17025		

The copy of each certificate can be downloaded from our web site: www.crc-lab.com

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2. Conducted Emission Measurement

Test Result : PASS

2.1 Limits for Emission Measurement

Test Standard: ETSI EN 301 489-1

ETSI EN 301 489-17 as §1.3 described

☑ Limits for conducted disturbances at the power mains

Frequency (MHz)	Used in i environment cen	or telecom.	Normal Used		
(IVII IZ)	Quasi-peak	Average	Quasi-peak	Average	
	(dBµV)	(dBµV)	(dBµV)	(dBµV)	
0.15 to 0.5	79	66	66 – 56	56 – 46	
0.5 to 5	73	60	56	46	
5 to 30	73	60	60	50	

Note 1- The lower limit shall apply at the transition frequency.

☑ Limits for conducted common mode disturbances at telecommunication ports

Frequency	Used in industrial environment or telecom. center				Normal Used			
(MHz)	Voltage	e Limits	Current Limits		Voltage	e Limits	Current Limits	
	Q.P.	Average	Q.P.	Average	Q.P.	Average	Q.P.	Average
	(dBµV)	(dBµV)	(dBµA)	(dBµA)	(dBµV)	(dBµV)	(dBµA)	(dBµA)
0.15 to 0.5	97 - 87	84 – 74	53 – 43	40 – 30	84 – 74	74 - 64	40 – 30	30 - 20
0.5 to 30	87	74	43	30	74	64	30	20

Note 1- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz.

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Note 2- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz for Class B equipment.

Note 2- The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of 150Ω to the telecommunication port under test.

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Test Standard: EN 55032

as §1.3 described

☑ Limits for conducted disturbances at the mains ports

Frequency	Class A E	quipment	Class B Equipment			
Frequency (MHz)	Quasi-peak	Average	Quasi-peak	Average		
(IVII IZ)	(dBµV)	(dBµV)	(dBµV)	(dBµV)		
0.15 to 0.5	79	66	66 – 56	56 – 46		
0.5 to 5	73	60	56	46		
5 to 30	73	60	60	50		

Note 1- The lower limit shall apply at the transition frequency.

Note 2- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz for Class B equipment.

☑ Limits for conducted common mode disturbances at telecommunication ports

	Class A Equipment				Class B Equipment				
Frequency	Voltage Limits		Current Limits		Voltage Limits		Current Limits		
(MHz)	Q.P.	Average	Q.P.	Average	Q.P.	Average	Q.P.	Average	
	(dBµV)	(dBµV)	(dBµA)	(dBµA)	(dBµV)	(dBµV)	(dBµA)	(dBµA)	
0.15 to 0.5	97 - 87	84 – 74	53 – 43	40 – 30	84 – 74	74 - 64	40 – 30	30 - 20	
0.5 to 30	87	74	43	30	74	64	30	20	

Note 1- The limit decreases linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5MHz.

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Note 2- The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of 150Ω to the telecommunication port under test.

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment		Serial No.	Calibration Date	Due Date	
Test Receiver	R&S	ESR/	April 15, 2019	April 15, 2020	
163t INCCCIVE	Νάο	102550	April 13, 2019	April 13, 2020	
LISN	SchwarzBeck	NSLK-8128-RC/	luk 2 2010	July 0, 2020	
LISIN	Scriwarzbeck	8128-383	July 2, 2019	July 2, 2020	
2 nd LISN	R&S	ENV4200/	May 5, 2010	May E 2020	
Z'' LISIN	Ras	833209/010	May 5, 2019	May 5, 2020	
	FCC	FCC-TLISN-T2-	Aug 2 2010	Aug 2 2020	
	FCC	02/20269	Aug. 2, 2019	Aug. 2, 2020	
ISN	TESEQ	ISN T400A/	Aug 2 2010	Aug. 2, 2020	
1014		28575	Aug. 2, 2019		
	TESEQ	□ ISN T800/	Aug 2 2010	Aug 2 2020	
		36191	Aug. 2, 2019	Aug. 2, 2020	
50Ω terminator	SHHNER	65 BNC-50-0-1/133	May 21, 2019	May 21, 2020	
JULY LETTINIALUI	SHINLIX	NE/005	Way 21, 2019	Way 21, 2020	
RF Switch	R&S	RSU28/	June 19, 2019	Dec. 19, 2019	
IXI SWILCII	Νάδ	338965/002	Julie 19, 2019		
RF Cable	N/A	N/A/	June 19, 2019	Dec. 19, 2019	
KF Cable	IN/A	C0052 ~ 56	Julie 19, 2019		
Test Software	Audix	e3/	NCR	NCR	
iesi Suliwale	Audix	V6.20110303a1	NOR		
TR5	ETS	TR5/	NCR	NCR	
shielded room	LINDGREN	15353-F	NOR	NOR	

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Note:

1. The calibrations are traceable to NML/ROC.

2. NCR : No Calibration Required.

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2 and the compliance is deemed to occur if no measured disturbance level exceeds the disturbance limit.

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Test Item	Uncertainty Value		
Conducted emissions	1.84dB		
using a LISN : NSLK-8128-RC	1.04UD		
Conducted emissions	1.92dB		
using a LISN :ENV 4200	1.92uB		
Conducted emissions	1.80dB		
using a ISN : FCC-TLISN-T2-02			
Conducted emissions	4 04 dD		
using a ISN : ISN T400A	1.94dB		
Conducted emissions	2.08dB		
using a ISN : ISN T800	2.U0UB		

Test Procedures 2.3

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

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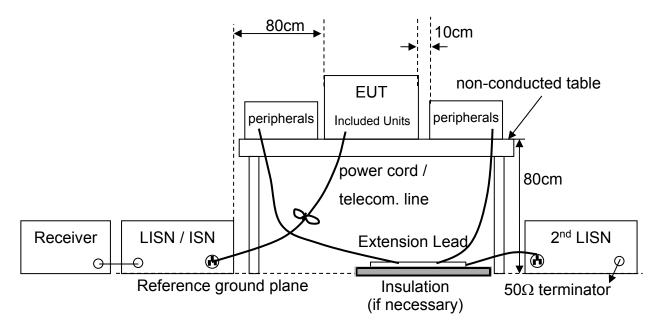
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- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters above the reference ground plane and 0.4 meters from the conducting wall of the shielded room. Also if the EUT is floor-standing equipment, it was placed on a non-conducted support with a height up to 0.15 meters above the reference ground plane.
- c. For EN 55032, all cables connecting to AE located outside the chamber shall drop directly to, but be insulated from, the RGP (or turntable). The thickness of the insulation shall not be more than 150 mm.
- d. Connect the EUT's power source / telecommunication lines to the appropriate power mains / peripherals through the LISN / ISN.
- e. All the other peripherals are connected to the 2nd LISN, if any.
- The LISN / ISN was placed 0.8 meters from the EUT and at least 0.8 meters from other units and other metal planes.
- g. Measure the conducted emissions on each power line (Neutral Line and Line 1 Hot side) of the EUT's power source by using the test receiver connected to the coupling RF output port of LISN.
- h. Rapidly scan the signal from 150kHz to 30MHz by using the receiver through the Maximum-Peak detector to determine those frequencies associated with higher emission levels for each measured line.
- Then measure the maximum level of conducted disturbance for each frequency found from step g. by using the receiver through the Quasi-Peak and Average detectors per CISPR 16-1.
- j. Record the level for each frequency and compare with the required limit.
- k. If required, measure the conducted emissions on telecommunication lines of EUT by using the test receiver connected to the coupling RF output port of ISN and repeat step g. to i.
- I. If the peak emission level is lower than the specified Average limit, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. or Average values will be measured and presented.

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2.4 Test Configurations



2.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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2.6 Test Results

Test Mode : Mode 1

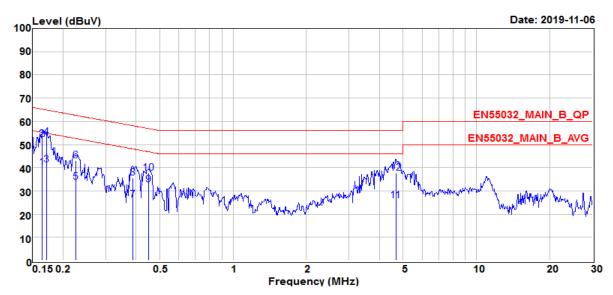
Test Voltage: 230Vac/50Hz to the power adapter

Tester : Sam Huang Temperature : 26°C

Humidity: 52%RH Frequency Range: 150kHz~30MHz

Report No.: S2O-A170-1903-297

IF Bandwidth: 9kHz Phase : Line



Site : TR5 Conduction Emission Chamber

Condition : EN55032_MAIN_B_QP NSLK_8128RC_WO LINE

Power : 230V/50Hz

Operator : Sam Huang T:26 H:52 P:1014

	Freq	Level	Read Level	Factor	Limit Line	Over Limit	Pol/Phase	Remark
	MHz	dBuV	dBuV	dB	dBuV	dB		
1	0.165	40.17	40.08	0.09	55.21	-15.04	LINE	Average
2	0.165	52.30	52.21	0.09	65.21	-12.91	LINE	QP
3	0.171	41.17	41.08	0.09	54.90	-13.73	LINE	Average
4	0.171	53.06	52.97	0.09	64.90	-11.84	LINE	QP
5	0.227	33.84	33.75	0.09	52.57	-18.73	LINE	Average
6	0.227	42.91	42.82	0.09	62.57	-19.66	LINE	QP
7	0.387	26.14	26.04	0.10	48.12	-21.98	LINE	Average
8	0.387	35.51	35.41	0.10	58.12	-22.61	LINE	QP
9	0.452	32.71	32.61	0.10	46.85	-14.14	LINE	Average
10	0.452	37.59	37.49	0.10	56.85	-19.26	LINE	QP
11	4.672	25.74	25.47	0.27	46.00	-20.26	LINE	Average
12	4.672	37.64	37.37	0.27	56.00	-18.36	LINE	QP

Note

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

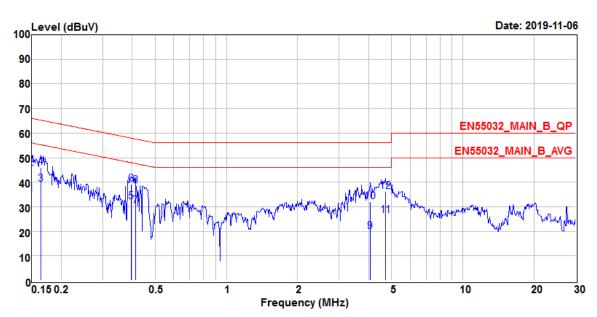
Test Mode Mode 1

Test Voltage 230Vac/50Hz to the power adapter :

Tester Temperature 26°C Sam Huang

52%RH **Humidity** Frequency Range 150kHz~30MHz

IF Bandwidth: 9kHz **Phase Neutral**



Site TR5 Conduction Emission Chamber Condition

: EN55032_MAIN_B_QP NSLK_8128RC_WO NEUTRAL

Power $230V/50\overline{H}z$

Operator : Sam Huang T:26 H:52 P:1014

	Freq	Level	Read Level	Factor	Limit Line	Over Limit	Pol/Phase	Remark
	MHZ	dBuV	dBuV	dB	dBuV	dB		
1	0.150	35.43	35.35	0.08	56.00	-20.57	NEUTRAL	Average
2	0.150	45.86	45.78	0.08	66.00	-20.14	NEUTRAL	QP
3	0.165	39.21	39.13	0.08	55.21	-16.00	NEUTRAL	Average
4	0.165	46.04	45.96	0.08	65.21	-19.17	NEUTRAL	QP
5	0.396	32.00	31.91	0.09	47.95	-15.95	NEUTRAL	Average
6	0.396	39.12	39.03	0.09	57.95	-18.83	NEUTRAL	QP
7	0.413	30.32	30.23	0.09	47.59	-17.27	NEUTRAL	Average
8	0.413	38.56	38.47	0.09	57.59	-19.03	NEUTRAL	QP
9	4.070	19.78	19.55	0.23	46.00	-26.22	NEUTRAL	Average
10	4.070	32.07	31.84	0.23	56.00	-23.93	NEUTRAL	QP
11	4.721	26.50	26.24	0.26	46.00	-19.50	NEUTRAL	Average
12	4.721	36.13	35.87	0.26	56.00	-19.87	NEUTRAL	QP

Note:

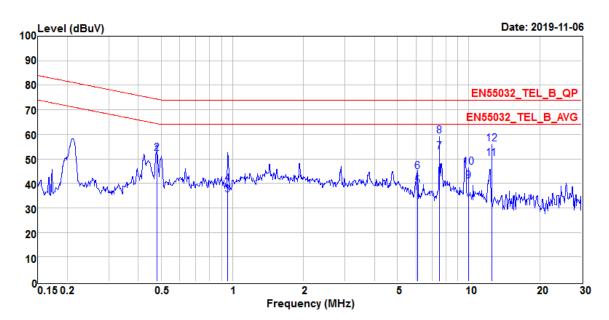
- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

Test Mode Mode 1

Test Voltage 230Vac/50Hz to the power adapter

Tester Temperature 26°C Sam Huang

52%RH **Humidity** Frequency Range: 150kHz~30MHz IF Bandwidth 9kHz **Phase** LAN for 10Mbps



Site : TR5 Conduction Emission Chamber

: EN55032_TEL_B_QP_ISN_T400A_CAT5-LAN_LINE Condition

: 230V/50Hz Power

: Sam Huang T:26 H:52 P:1014 Operator |

		Read		Limit	Over		
Freq	Level	Level	Factor	Line	Limit	Pol/Phase	Remark
MHz	dBuV	dBuV	dB	dBuV	dB		
0.479	51.56	41.84	9.72	64.36	-12.80	LINE	Average
0.479	52.11	42.39	9.72	74.36	-22.25	LINE	QP
0.953	35.38	25.76	9.62	64.00	-28.62	LINE	Average
0.953	39.92	30.30	9.62	74.00	-34.08	LINE	QP
6.089	38.90	29.31	9.59	64.00	-25.10	LINE	Average
6.089	44.78	35.19	9.59	74.00	-29.22	LINE	QP
7.500	52.98	43.38	9.60	64.00	-11.02	LINE	Average
7.500	59.42	49.82	9.60	74.00	-14.58	LINE	QP
10.000	40.88	31.26	9.62	64.00	-23.12	LINE	Average
10.000	46.67	37.05	9.62	74.00	-27.33	LINE	QP
12.500	50.17	40.52	9.65	64.00	-13.83	LINE	Average
12.500	56.05	46.40	9.65	74.00	-17.95	LINE	QP
	MHz 0.479 0.479 0.953 0.953 6.089 6.089 7.500 7.500 10.000 10.000 12.500	MHz dBuV 0.479 51.56 0.479 52.11 0.953 35.38 0.953 39.92 6.089 38.90 6.089 44.78 7.500 52.98 7.500 59.42 10.000 40.88 10.000 46.67 12.500 50.17	MHz dBuV dBuV 0.479 51.56 41.84 0.479 52.11 42.39 0.953 35.38 25.76 0.953 39.92 30.30 6.089 38.90 29.31 6.089 44.78 35.19 7.500 52.98 43.38 7.500 59.42 49.82 10.000 40.88 31.26 10.000 46.67 37.05 12.500 50.17 40.52	Freq Level Level Factor MHz dBuV dBuV dB 0.479 51.56 41.84 9.72 0.479 52.11 42.39 9.72 0.953 35.38 25.76 9.62 0.953 39.92 30.30 9.62 6.089 38.90 29.31 9.59 7.500 52.98 43.38 9.60 7.500 59.42 49.82 9.60 10.000 40.88 31.26 9.62 10.000 46.67 37.05 9.62 12.500 50.17 40.52 9.65	Freq Level Level Factor Line MHz dBuV dBuV dB dBuV 0.479 51.56 41.84 9.72 64.36 0.479 52.11 42.39 9.72 74.36 0.953 35.38 25.76 9.62 64.00 0.953 39.92 30.30 9.62 74.00 6.089 38.90 29.31 9.59 64.00 7.500 52.98 43.38 9.60 64.00 7.500 59.42 49.82 9.60 74.00 10.000 40.88 31.26 9.62 64.00 10.000 46.67 37.05 9.62 74.00 12.500 50.17 40.52 9.65 64.00	Freq Level Level Factor Line Limit MHz dBuV dBuV dB dBuV dB 0.479 51.56 41.84 9.72 64.36 -12.80 0.479 52.11 42.39 9.72 74.36 -22.25 0.953 35.38 25.76 9.62 64.00 -28.62 0.953 39.92 30.30 9.62 74.00 -34.08 6.089 38.90 29.31 9.59 64.00 -25.10 6.089 44.78 35.19 9.59 74.00 -29.22 7.500 52.98 43.38 9.60 64.00 -11.02 7.500 59.42 49.82 9.60 74.00 -14.58 10.000 40.88 31.26 9.62 64.00 -27.33 12.500 50.17 40.52 9.65 64.00 -13.83	Freq Level Factor Line Limit Pol/Phase MHz dBuV dBuV dB dBuV dB 0.479 51.56 41.84 9.72 64.36 -12.80 LINE 0.479 52.11 42.39 9.72 74.36 -22.25 LINE 0.953 35.38 25.76 9.62 64.00 -28.62 LINE 0.953 39.92 30.30 9.62 74.00 -34.08 LINE 6.089 38.90 29.31 9.59 64.00 -25.10 LINE 6.089 44.78 35.19 9.59 74.00 -29.22 LINE 7.500 52.98 43.38 9.60 64.00 -11.02 LINE 7.500 59.42 49.82 9.60 74.00 -14.58 LINE 10.000 40.88 31.26 9.62 64.00 -23.12 LINE 10.000 46.67 37.05 9.62 74.00

Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN/ ISN.
- 3. Q.P. is abbreviation of quasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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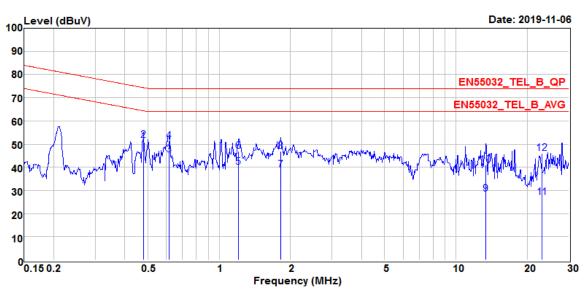
Test Mode Mode 1

Test Voltage 230Vac/50Hz to the power adapter

26°C **Tester** : Sam Huang **Temperature** :

150kHz~30MHz Humidity 52%RH Frequency Range:

IF Bandwidth: **Phase** LAN for 100Mbps 9kHz



Site TR5 Conduction Emission Chamber

Condition EN55032_TEL_B_QP_ISN_T400A_CAT5-LAN_LINE

Power 230V/50Hz

Sam Huang T:26 H:52 P:1014 Operator |

			Read		Limit	Over		
	Freq	Level	Level	Factor	Line	Limit	Pol/Phase	Remark
	MHz	dBuV	dBuV	dB	dBuV	dB		
1	0.479	51.16	41.44	9.72	64.36	-13.20	LINE	Average
2	0.479	51.71	41.99	9.72	74.36	-22.65	LINE	QP
3	0.614	45.31	35.63	9.68	64.00	-18.69	LINE	Average
4	0.614	51.27	41.59	9.68	74.00	-22.73	LINE	QP
5	1.210	39.93	30.32	9.61	64.00	-24.07	LINE	Average
6	1.210	46.81	37.20	9.61	74.00	-27.19	LINE	QP
7	1.819	38.97	29.38	9.59	64.00	-25.03	LINE	Average
8	1.819	46.80	37.21	9.59	74.00	-27.20	LINE	QP
9	13.408	28.53	18.88	9.65	64.00	-35.47	LINE	Average
10	13.408	41.04	31.39	9.65	74.00	-32.96	LINE	QP
11	23.128	27.04	17.30	9.74	64.00	-36.96	LINE	Average
12	23.128	45.93	36.19	9.74	74.00	-28.07	LINE	QP

Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN/ ISN.
- 3. Q.P. is abbreviation of quasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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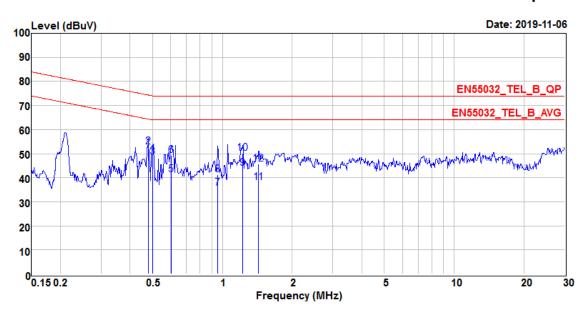
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Test Mode Mode 1

Test Voltage 230Vac/50Hz to the power adapter

Tester Temperature 26°C Sam Huang

52%RH **Humidity** Frequency Range: 150kHz~30MHz **IF Bandwidth** 9kHz **Phase** LAN for 1Gbps



Site TR5 Conduction Emission Chamber

EN55032_TEL_B_QP ISN_T800_CAT5-LAN LINE Condition

 $230V/50\overline{H}z$ Power

T:26 H:52 P:1014 Operator Sam Huang

			Read		Limit	Over		
	Freq	Level	Level	Factor	Line	Limit	Pol/Phase	Remark
	MHZ	dBuV	dBuV	dB	dBuV	dB		
1	0.479	52.15	42.36	9.79	64.36	-12.21	LINE	Average
2	0.479	52.70	42.91	9.79	74.36	-21.66	LINE	QP
3	0.499	48.76	38.98	9.78	64.01	-15.25	LINE	Average
4	0.499	49.77	39.99	9.78	74.01	-24.24	LINE	QP
5	0.601	41.29	31.54	9.75	64.00	-22.71	LINE	Average
6	0.601	49.20	39.45	9.75	74.00	-24.80	LINE	QP
7	0.953	35.60	25.90	9.70	64.00	-28.40	LINE	Average
8	0.953	41.16	31.46	9.70	74.00	-32.84	LINE	QP
9	1.223	44.00	34.31	9.69	64.00	-20.00	LINE	Average
10	1.223	50.22	40.53	9.69	74.00	-23.78	LINE	QP
11	1.433	38.09	28.41	9.68	64.00	-25.91	LINE	Average
12	1.433	45.61	35.93	9.68	74.00	-28.39	LINE	QP

Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN/ ISN.
- Q.P. is abbreviation of quasi-peak. 3.
- If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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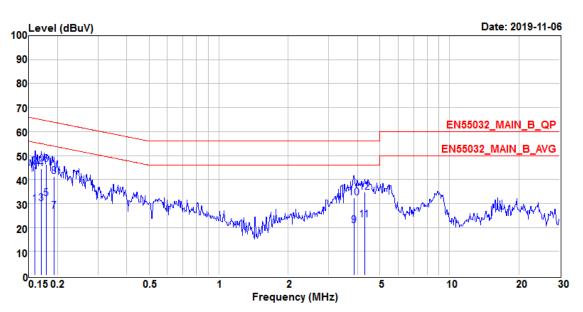
Test Mode Mode 1

Test Voltage 120Vac/60Hz to the power adapter

Tester Temperature 26°C Sam Huang

52%RH **Humidity** Frequency Range 150kHz~30MHz

IF Bandwidth 9kHz **Phase** Line



Site : TR5 Conduction Emission Chamber Condition

: EN55032_MAIN_B_QP NSLK_8128RC_WO LINE

: 120V/60Hz Power

T:26 H:52 P:1014 Operator : Sam Huang

			Read		Limit	Over		
	Freq	Level	Level	Factor	Line	Limit	Pol/Phase	Remark
		dBuV	dBuV	dB	dBuV	dB		
	11112	abav	abav	ab	abav	ub.		
1	0.160	29.64	29.55	0.09	55.47	-25.83	LINE	Average
2	0.160	45.42	45.33	0.09	65.47	-20.05	LINE	QP
3	0.170	30.06	29.97	0.09	54.94	-24.88	LINE	Average
4	0.170	44.49	44.40	0.09	64.94	-20.45	LINE	QP
5	0.180	32.16	32.07	0.09	54.50	-22.34	LINE	Average
6	0.180	46.41	46.32	0.09	64.50	-18.09	LINE	QP
7	0.193	26.61	26.52	0.09	53.89	-27.28	LINE	Average
8	0.193	41.34	41.25	0.09	63.89	-22.55	LINE	QP
9	3.860	20.83	20.59	0.24	46.00	-25.17	LINE	Average
10	3.860	32.44	32.20	0.24	56.00	-23.56	LINE	QP
11	4.292	23.25	22.99	0.26	46.00	-22.75	LINE	Average
12	4.292	34.59	34.33	0.26	56.00	-21.41	LINE	QP

Note:

- 1. Emission Level = reading value + correction factor.
- Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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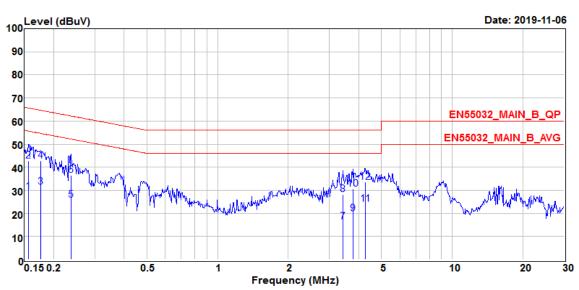
Test Mode : Mode 1

Test Voltage: 120Vac/60Hz to the power adapter

Tester : Sam Huang Temperature : 26°C

Humidity: 52%RH Frequency Range: 150kHz~30MHz

IF Bandwidth: 9kHz Phase: Neutral



Site : TR5 Conduction Emission Chamber

Condition : EN55032_MAIN_B_QP NSLK_8128RC_WO NEUTRAL

Power : $120V/60\overline{H}z$

Operator : Sam Huang T:26 H:52 P:1014
Read Limit Over

	Freq	Level	Level	Factor	Line	Limit	Pol/Phase	Remark
	MHz	dBuV	dBuV	dB	dBuV	dB		
1	0.156	29.27	29.19	0.08	55.65	-26.38	NEUTRAL	Average
2	0.156	42.62	42.54	0.08	65.65	-23.03	NEUTRAL	QP
3	0.177	31.56	31.48	0.08	54.64	-23.08	NEUTRAL	Average
4	0.177	42.69	42.61	0.08	64.64	-21.95	NEUTRAL	QP
5	0.238	25.81	25.73	0.08	52.17	-26.36	NEUTRAL	Average
6	0.238	36.57	36.49	0.08	62.17	-25.60	NEUTRAL	QP
7	3.417	16.43	16.22	0.21	46.00	-29.57	NEUTRAL	Average
8	3.417	28.11	27.90	0.21	56.00	-27.89	NEUTRAL	QP
9	3.779	20.00	19.77	0.23	46.00	-26.00	NEUTRAL	Average
10	3.779	30.56	30.33	0.23	56.00	-25.44	NEUTRAL	QP
11	4.269	23.90	23.65	0.25	46.00	-22.10	NEUTRAL	Average
12	4.269	33.43	33.18	0.25	56.00	-22.57	NEUTRAL	QP

Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + insertion loss of LISN.
- 3. Q.P. is abbreviation of quasi-peak.
- 4. If the limit for the measurement with the average detector is met when using a receiver with a quasi-peak detector, the EUT shall be deemed to meet both limits.

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3. Radiated Emission Measurement

Test Result : PASS

3.1 Limits for Emission Measurement

Type of EUT	Highest frequency generated or used in the device or on which the device	Upper frequency of measurement range
	operates or tunes (MHz)	(MHz)
	Below 108	1000
	108 - 500	2000
	500 - 1000	5000
		5 th harmonic of the highest
$\overline{\mathbf{V}}$	Above 1000	frequency or 6GHz,
		whichever is lower

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Test Standard: ETSI EN 301 489-1

ETSI EN 301 489-17 as §1.3 described

☑ Limits for radiated disturbances at a measuring distance of 10m

Frequency	Used in industrial environment or telecom. center	Normal Used	
(MHz)	Quasi-peak (dBμV/m)	Quasi-peak (dBμV/m)	
30 to 230	40	30	
230 to 1000	47	37	

Note 1- The lower limit shall apply at the transition frequency.

Note 2- Additional provisions may be required for cases where interference occurs.

☑ Limits for radiated disturbances at a measuring distance of 3m

Frequency	Used in i environmen cer	t or telecom.	Norma	I Used	
(GHz)	Peak (dBµV/m)	Average (dBµV/m)	Peak (dBµV/m)	Average (dBµV/m)	
1 to 3	76	56	70	50	
3 to 6	80	60	74	54	
Note 1- The lower li	Note 1- The lower limit shall apply at the transition frequency.				

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Test Standard: EN 55032

as §1.3 described

☑ Limits for radiated disturbances at a measuring distance of 10m

Fraguency	Class A Equipment	Class B Equipment	
Frequency (MHz)	Quasi-peak (dBμV/m)	Quasi-peak (dΒμV/m)	
30 to 230	40	30	
230 to 1000	47	37	

Note 1- The lower limit shall apply at the transition frequency.

Note 2- Additional provisions may be required for cases where interference occurs.

☑ Limits for radiated disturbances at a measuring distance of 3m

Frequency	Class A E	quipment	Class B Equipment		
(GHz)	Peak (dBµV/m)	Average (dBµV/m)	Peak (dBµV/m)	Average (dBµV/m)	
1 to 3	76	56	70	50	
3 to 6	80	60	74	54	
Note 1- The lower limit shall apply at the transition frequency.					

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Test Instruments 3.2

☑ Below 1GHz measurement

Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
EMI Test Receiver	R&S	ESR/ 102308	July 11, 2019	July 11, 2020
Bilog Antenna with 5 dB Attenuator	SCHWARZBEC K & Mini- Circuits	VULB 9168 & BW- N5W5+ / VULB 9168-618 & 001	June 10, 2019	June 10, 2020
Bilog Antenna with 5 dB Attenuator	SCHWARZBEC K & Mini- Circuits	VULB 9168 & BW- N5W5+/ VULB 9168-619 & 002	June 27, 2019	June 27, 2020
Pre-Amplifier	EMCI	EMCI EMC9135/ 980630		Dec. 29, 2019
Pre-Amplifier	EMCI	EMC9135/ 980550	June 29, 2019	Dec. 29, 2019
Spectrum Analyzer	R&S	FSP7/ 100106	March 21, 2019	March 21, 2020
Spectrum Analyzer	R&S	FSP7/ 100384	Feb. 13, 2019	Feb. 13, 2020
RF Cable	JYEBAO	0214/ C0058 + C0049 + C0049-2 + RSU + C0050-3	June 29, 2019	Dec. 29, 2019
RF Cable	JYEBAO	0214/ C0059 + C0050 + C0050-2 + RSU + C0050-3	June 29, 2019	Dec. 29, 2019
Test Software	Audix	e3/ V6.20110303a1	NCR	NCR
TR1 Semi - anechoic Chamber	ETS. LINDGREN	TR1/ 17627-B	Feb. 23, 2019	Feb. 23, 2020

Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the chamber TR1 listed above is the date of NSA measurement.

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Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Horn Antenna	EMCO	3117/ 0082847	Nov. 20, 2018	Nov. 20, 2019
Bore-sight Antenna Mast	Sunol	TLT2/ 051110-5	NCR	NCR
Pre-Amplifier	MITEQ	TTA1800-30-HG-N-M/ 1904295	Nov. 20, 2018	Nov. 20, 2019
RF Cable	Suhner	Sucoflex 106P / C0091	Nov. 20, 2018	Nov. 20, 2019
MXA Signal Analyzer	KeySight	N9020A/ MY54420147	July 2, 2019	July 2, 2020
Test Software	Audix	e3/ V9 20150907c	NCR	NCR
TR1 Semi- anechoic chamber with absorber	ETS. LINDGREN	TR1/ 17627-B	Feb. 23, 2019	Feb. 23, 2020

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Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the chamber TR1 listed above is the date of site VSWR measurement.

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Measurement Uncertainty

The assessed measurement uncertainty with a suitable coverage factor K to ensure 95% confidence level for the normal distribution are shown as below, the values are less than U_{cispr} in table 1 of CISPR 16-4-2 and the compliance is deemed to occur if no measured disturbance level exceeds the disturbance limit.

Test Site	Polarization	Frequency Range		
(Measuring distance)	i Giarization	30MHz ~ 200MHz	200MHz ~ 1000MHz	
TR1(10m)	Horizontal	3.98dB	3.10dB	
	Vertical	3.76dB	3.28dB	

Test Site	Polarization	Frequency Range
(Measuring distance)	i olarization	1GHz ~ 6GHz
TR1(3m)	Horizontal	4.70dB
	Vertical	4.78dB
TR300(3m)	Horizontal	5.06dB
	Vertical	4.98dB

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3.3 Test Procedures

Below 1GHz measurement

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

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- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters above the reference ground plane and 10 meters away from the interference receiving antenna in the semi-anechoic chamber.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height up to 0.15 meters above the reference ground plane and 10 meters away from the interference-receiving antenna in the semi-anechoic chamber.
- d. For EN 55032, all cables connecting to AE located outside the chamber shall drop directly to, but be insulated from, the RGP (or turntable). The thickness of the insulation shall not be more than 150 mm.
- e. Rapidly sweep the signal from 30MHz to 1GHz by using the spectrum through the Maximum-peak detector.
- f. Rotate the EUT from 0° to 360° and position the receiving antenna at heights from 1 to 4 meters above the reference ground plane continuously to determine at least three frequencies associated with higher emission levels and record them.
- g. Then measure each frequency found from step e. by using the spectrum with rotating the EUT and positioning the receiving antenna height to determine the maximum level.
- h. Finely tune the antenna and turntable around the recorded position of each frequency found from step f. by using the receiver through the Quasi-Peak detector per CISPR 16-1 to find out where the maximum level occurred.
- i. Record frequency, azimuth angle of the turntable, height, and polarization of the receiving antenna and compare the maximum level with the required limit.
- j. Change the receiving antenna to another polarization to measure radiated emission by following step d. to h. again.
- k. If the peak emission level measured from step e. is 4dB lower than the limit specified, then the emission values presented will be the peak value only. Otherwise, accurate Q.P. value will be measured and presented.

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Above 1GHz measurement

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

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- b. If the EUT is tabletop equipment, it should be placed on a non-conducted table with a height of 0.8 meters above the reference ground plane and 3 meters away from the interference receiving antenna in the fully-anechoic chamber.
- c. If the EUT is floor-standing equipment, it should be placed on a non-conducted support with a height up to 0.15 meters above the reference ground plane and 3 meters away from the interference-receiving antenna in the fully-anechoic chamber.
- d. For EN 55032, all cables connecting to AE located outside the chamber shall drop directly to, but be insulated from, the RGP (or turntable). The thickness of the insulation shall not be more than 150 mm.
- e. Rapidly sweep the signal from 1GHz to the upper frequency of measurement range by using the spectrum through the Maximum-peak detector.
- f. If the 3dB beamwidth of the receiving antenna (minima w is 2.8m @ 1GHz to 6GHz while test distance is 3m) encompasses EUT height, the center of the receiving antenna will be fixed at the height of the center of the EUT. If w of a 1m-height receiving antenna encompasses the whole EUT, the antenna will be fixed at 1m height. For any EUT with the height larger than w, the receiving antenna will travelled vertically so that the antenna beam scans the whole EUT.
- g. Rotate the EUT from 0° to 360° continuously and position the receiving antenna at specified height above the reference ground plane to determine the frequencies associated with higher emission levels and record them.
- h. Then measure each frequency found from step e. by using the spectrum with rotating the EUT to determine the maximum peak and average level.
- i. Record frequency, azimuth angle of the turntable and compare the maximum level with the required limit.
- j. Change the receiving antenna to another polarization to measure radiated emission by following step d. to g. again.

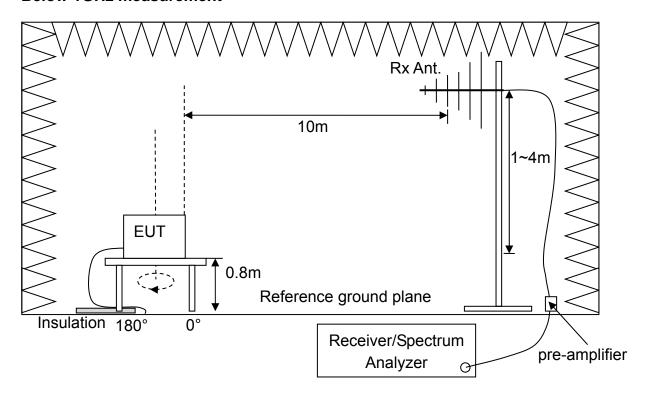
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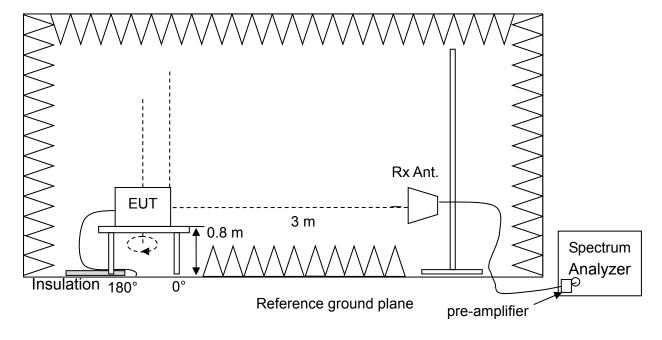
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3.4 Test Configurations

Below 1GHz measurement



Above 1GHz measurement



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Photographs of the Test Configurations 3.5

Please refer to the Attachment 1 of the present report.

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Test Results 3.6

Radiated Emission Measurement below 1000MHz

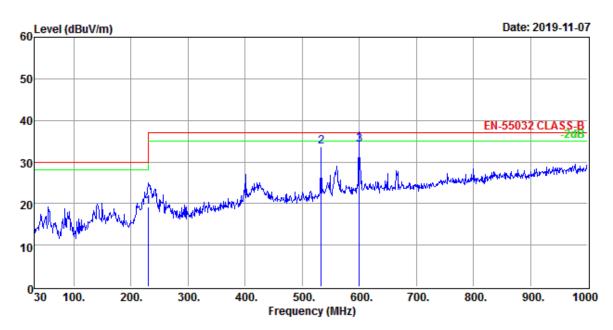
Test Mode Mode 1

Test Voltage 110Vac/60Hz to the power adapter

24°C **Tester** Jeffry **Temperature** :

Humidity 56%RH **Frequency Range** 30MHz~1GHz

Polarization IF Bandwidth: 120kHz Horizontal



Site : TR1 10M RE CHAMBER

Condition : EN-55032 CLASS-B 10m VULB_9168-619 HORIZONTAL

Power : 110V/60HZ

: Jeffry (1M) 'T:24 'H:56 'P:1014 Operator

			Read			Over	A/Pos	T/Pos		
	Freq	Level	Level	Factor	Line	Limit			Pol/Phase	Remark
-	MHz	dBuV/m	dBuV	dB/m	dBuV/m	dB		deg		
								_		
1	230.000	19.11	37.95	-18.84	30.00	-10.89	399	131	HORIZONTAL	QP
2	533.326	33.66	43.63	-9.97	37.00	-3.34	144	266	HORIZONTAL	QP
3	599.977	34.16	42.38	-8.22	37.00	-2.84	102	277	HORIZONTAL	QP

Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor – gain of pre-amplifier.
- Q.P is abbreviation of quasi-peak.

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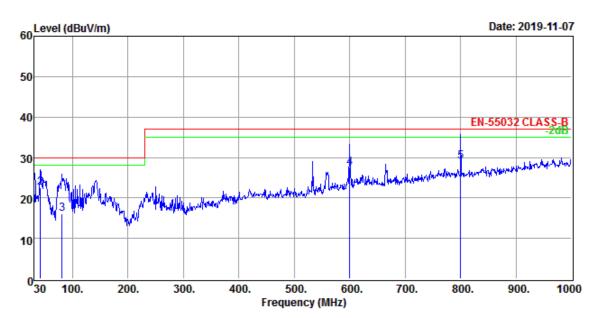
Test Mode : Mode 1

Test Voltage: 110Vac/60Hz to the power adapter

Tester: Jeffry **Temperature**: 24°C

Humidity: 56%RH **Frequency Range**: 30MHz~1GHz

IF Bandwidth: 120kHz Polarization: Vertical



Site : TR1 10M RE CHAMBER

Condition : EN-55032 CLASS-B 10m VULB_9168-618 VERTICAL

Power : 110V/60Hz

Operator : Jeffry (1M) 'T:24 'H:56 'P:1014

	Freq	Level				Over Limit			Pol/Phase	Remark
	MHz	dBuV/m	dBuV	dB/m	dBuV/m	dB	cm	deg		
1	30.313	18.04	37.05	-19.01	30.00	-11.96	104	96	VERTICAL	QP
2	41.479	22.43	40.31	-17.88	30.00	-7.57	105	126	VERTICAL	QP
3	80.486	16.14	38.15	-22.01	30.00	-13.86	105	185	VERTICAL	QP
4	600.014	27.52	34.72	-7.20	37.00	-9.48	285	61	VERTICAL	QP
5	800.054	28.91	32.59	-3.68	37.00	-8.09	193	0	VERTICAL	QP

Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.
- 3. Q.P is abbreviation of quasi-peak.

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Radiated Emission Measurement above 1000MHz

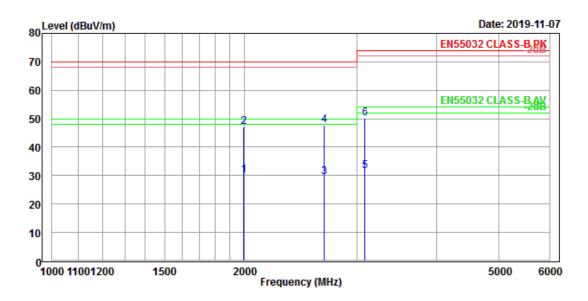
Test Mode : Mode 1

Test Voltage: 110Vac/60Hz to the power adapter

Tester: Jack **Temperature**: 24°C

Humidity: 55%RH Frequency Range: 1GHz~6GHz

IF Bandwidth: 1MHz Polarization: Horizontal



Condition : EN55032 CLASS-B PK 3m EMCO_3117_82847 Horizontal

: SWT:Auto DET:Positive

POWER : 110V/60Hz

OPERATOR : Jack, T: 24, H: 55, P: 1011

	Freq	Level	Read Level	Factor	Limit Line	Over Limit	APos	TPos	Pol/Phase	Remark
	MHz	dBuV/m	dBu V	dB/m	dBuV/m	dB	cm	deg		
1	1993.155	29.98	47.86	-17.88	50.00	-20.02	100	216	Horizontal	Average
2	1994.296	47.07	64.95	-17.88	70.00	-22.93	100	209	Horizontal	Peak
3	2663.634	29.36	45.90	-16.54	50.00	-20.64	100	259	Horizontal	Average
4	2664.341	47.73	64.27	-16.54	70.00	-22.27	100	264	Horizontal	Peak
5	3088.142	31.53	47.72	-16.19	54.00	-22.47	100	255	Horizontal	Average
6	3089.347	50.22	66.40	-16.18	74.00	-23.78	100	248	Horizontal	Peak

Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

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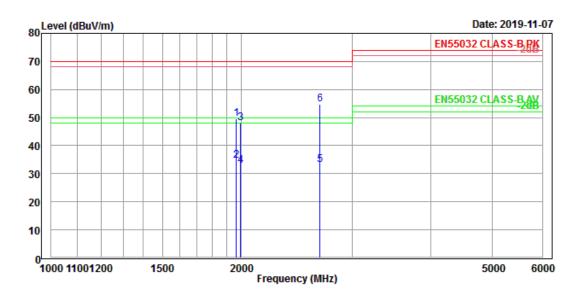
Test Mode: Mode 1

Test Voltage: 110Vac/60Hz to the power adapter

Tester: Jack **Temperature**: 24°C

Humidity: 55%RH Frequency Range: 1GHz~6GHz

IF Bandwidth: 1MHz Polarization: Vertical



Condition : EN55032 CLASS-B PK 3m EMCO_3117_82847 VERTICAL

: SWT:Auto DET:Positive

POWER : 110V/60Hz

OPERATOR : Jack, T: 24, H: 55, P: 1011

	Freq	Level	Read Level	Factor	Limit Line		APos	TPos	Pol/Phase	Remark
	MHz	dBuV/m	dBuV	dB/m	dBuV/m	dB	cm	deg		
1	1964.412	49.56	67.51	-17.95	70.00	-20.44	100	24	VERTICAL	Peak
2	1965.236	34.59	52.54	-17.95	50.00	-15.41	100	15	VERTICAL	Average
3	1994.741	48.03	65.91	-17.88	70.00	-21.97	100	5	VERTICAL	Peak
4	1995.719	32.72	50.60	-17.88	50.00	-17.28	100	1	VERTICAL	Average
5	2661.771	33.17	49.70	-16.53	50.00	-16.83	100	23	VERTICAL	Average
6	2662.417	54.63	71.16	-16.53	70.00	-15.37	100	30	VERTICAL	Peak

Note:

- 1. Emission Level = reading value + correction factor.
- 2. Correction factor = cable loss + antenna factor gain of pre-amplifier.

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4. Harmonic Current Emission Measurement

Test Result : PASS

4.1 Limits for Emission Measurement

☐ Limits for Class A equipment

Harmonic order (n)	Maximum permissible	Harmonic order (n)	Maximum permissible
Odd harmonics	harmonic current (A)	Even Harmonics	harmonic current (A)
3	2.30	2	1.08
5	1.14	4	0.43
7	0.77	6	0.3
9	0.40	8 ≦ n ≦40	0.23 8/n
11	0.33		
13	0.21		
$15 \leq n \leq 39$	0.15 15/n		

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☐ Limits for Class B equipment

It shall not exceed the values give in class A multiplied by a factor of 1.5.

☐ Limits for Class C equipment

Harmonic order (n)	Maximum permissible harmonic current expressed as a percentage of the input current at the fundamental frequency %
2	2
3	30 · λ (λ is the circuit power factor)
5	10
7	7
9	5
11 ≤ n ≤ 39	3
(odd harmonics only)	

☑ Limits for Class D equipment

	Maximum permissible harmonic	Maximum permissible harmonic
Harmonic order (n)	·	•
, ,	current per watt (mA/W)	current (A)
3	3.4	2.30
5	1.9	1.14
7	1.0	0.77
9	0.5	0.40
11	0.35	0.33
13 ≤ n ≤ 39	3.85/n	See class A
(odd harmonics only)		

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Test Instruments 4.2

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Wandacturer	Serial No.	Calibration Date	Due Date	
Power Source		5001ix-208/	Oct 14 2010	Oct 14 2020	
Power Source	California	56619	Oct. 14, 2019	Oct. 14, 2020	
Dower Apolyzor	Instrument	PACS-1/	Oct. 14, 2019	Oct. 14, 2020	
Power Analyzer		72398	OCI. 14, 2019		
Test Software	C.I.	CTS 4/	NCD	NCR	
Test Software	C.I.	Ver. 4.24	NCR		
TR7	ETS.	S. TR7/		NCD	
shielded room	LINDGREN	15353-D	NCR	NCR	

Note:

- The calibrations are traceable to NML/ROC.
- NCR: No Calibration Required. 2.

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

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- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters in the shielded room.
- d. Decide the classification of the EUT as following:

Class A: - balanced three-phase equipment

- household appliances, excluding equipment identified as class D
- tools, excluding portable tools
- dimmers for incandescent lamps
- audio equipment
- equipments not specified in one of the three other classes

Class B: - portable tools

- arc welding equipment which is not professional equipment.

Class C: - lighting equipment

Class D: - Equipment specified power less than or equal to 600W of the following types

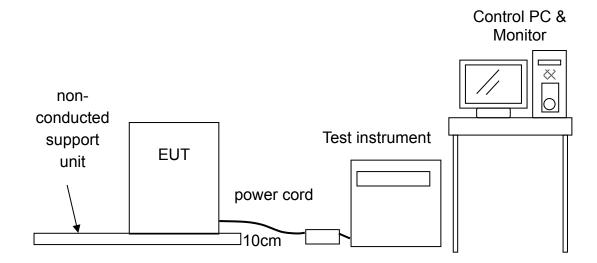
- personal computers and personal computer monitors
- television receivers
- refrigerators and freezers having one or more variable-speed drives to control compressor motor(s).
- e. Connects the EUT's power source to the mains power supplied by the test instrument. Turn on the EUT.
- Operating the EUT as required and measuring the harmonic current emissions on the current carrying lines of EUT's power source.

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4.4 Test Configurations



4.5 Photographs of the Test Configurations

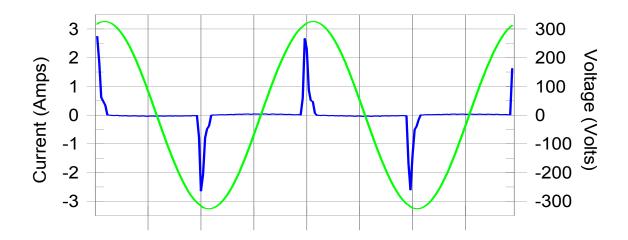
Please refer to the Attachment 1 of the present report.

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4.6 Test Results

Test Mode : Mode 1
Tester : Jeff
Temperature : 22°C
Humidity : 56%RH

Test Frequency (Hz)	50
Test Voltage (V)	230
Test observation period (Minutes)	10
Reference Current (A)	0.509
Power Factor	0.385
Power (Watt)	44.7
Total Harmonic Current, THC (A)	0.463
Total Harmonic Distortion, THD (%)	227.5



Note: The EUT power level is below 75.0 Watts and therefore has no defined limits.

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Test Raw Data:

Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2	0.000	0.000	N/A	0.001	0.000	N/A	N/L
3	0.192	0.152	N/A	0.193	0.228	N/A	N/L
4	0.001	0.000	N/A	0.001	0.000	N/A	N/L
5	0.183	0.085	N/A	0.183	0.127	N/A	N/L
6	0.001	0.000	N/A	0.001	0.000	N/A	N/L
7	0.170	0.045	N/A	0.170	0.067	N/A	N/L
8	0.001	0.000	N/A	0.001	0.000	N/A	N/L
9	0.154	0.022	N/A	0.154	0.034	N/A	N/L
10	0.001	0.000	N/A	0.001	0.000	N/A	N/L
11	0.137	0.016	N/A	0.138	0.023	N/A	N/L
12	0.001	0.000	N/A	0.001	0.000	N/A	N/L
13	0.121	0.013	N/A	0.121	0.020	N/A	N/L
14	0.000	0.000	N/A	0.001	0.000	N/A	N/L
15	0.106	0.012	N/A	0.107	0.017	N/A	N/L
16	0.000	0.000	N/A	0.001	0.000	N/A	N/L
17	0.094	0.010	N/A	0.095	0.015	N/A	N/L
18	0.001	0.000	N/A	0.001	0.000	N/A	N/L
19	0.085	0.009	N/A	0.086	0.014	N/A	N/L
20	0.001	0.000	N/A	0.001	0.000	N/A	N/L
21	0.079	0.008	N/A	0.080	0.012	N/A	N/L
22	0.001	0.000	N/A	0.002	0.000	N/A	N/L
23	0.075	0.007	N/A	0.076	0.011	N/A	N/L
24	0.001	0.000	N/A	0.002	0.000	N/A	N/L
25	0.070	0.007	N/A	0.071	0.010	N/A	N/L
26	0.001	0.000	N/A	0.002	0.000	N/A	N/L
27	0.065	0.006	N/A	0.066	0.010	N/A	N/L
28	0.001	0.000	N/A	0.002	0.000	N/A	N/L
29	0.058	0.006	N/A	0.060	0.009	N/A	N/L
30	0.001	0.000	N/A	0.002	0.000	N/A	N/L
31	0.051	0.006	N/A	0.052	0.008	N/A	N/L
32	0.001	0.000	N/A	0.002	0.000	N/A	N/L
33	0.043	0.005	N/A	0.043	0.008	N/A	N/L
34	0.001	0.000	N/A	0.002	0.000	N/A	N/L
35	0.034	0.005	N/A	0.035	0.007	N/A	N/L
36	0.001	0.000	N/A	0.002	0.000	N/A	N/L
37	0.026	0.005	N/A	0.026	0.007	N/A	N/L
38	0.001	0.000	N/A	0.001	0.000	N/A	N/L
39	0.019	0.004	N/A	0.019	0.007	N/A	N/L
40	0.001	0.000	N/A	0.001	0.000	N/A	N/L

Harmonic currents less than 0.6% of the input current measured under the test conditions, or less than 5 mA, whichever is greater, are disregarded.

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5. Voltage Fluctuations and Flickers Emission Measurement

Test Result : PASS

5.1 Limits for Emission Measurement

- the short-term flicker indicator, P_{st}, shall not be greater than 1.0;
- the long-term flicker indicator, P_{lt}, shall not be greater than 0.65;
- the relative steady-state voltage change, dc, shall not exceed 3.3%;
- the voltage change with time, d(t), during a voltage change shall not exceed 3.3% for more than 500ms.
- the maximum relative voltage change, d_{max}, shall not exceed
 - ☑ a) 4% without additional conditions;
 - □ b) 6% for equipment which is switched manually
 - □ c) 7% for equipment which is attended whilst in use

5.2 Test Instruments

Test Site and	Manufacturer	Model No./	Last	Calibration
Equipment	Wanulacturer	Serial No.	Calibration Date	Due Date
Power Source	California	5001ix-208/ 56619	Oct. 14, 2019	Oct. 14, 2020
Power Analyzer	Instrument	PACS-1/ 72398	Oct. 14, 2019	Oct. 14, 2020
Test Software	C.I.	CTS 4/ Ver. 4.24	NCR	NCR
TR7 shielded room	ETS. LINDGREN	TR7/ 15353-D	NCR	NCR

Note:

1. The calibrations are traceable to NML/ROC.

2. NCR: No Calibration Required.

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5.3 Test Procedures

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

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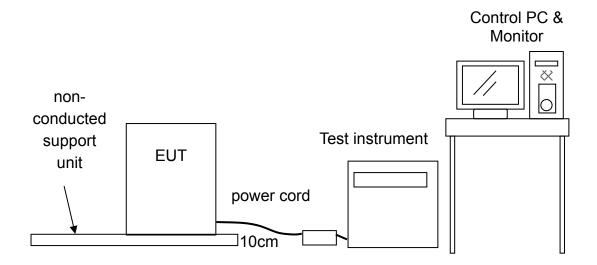
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- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters in the shielded room.
- d. Decide the type of EUT to define the d_{max} limit and its corresponding test methods described in the relative standard.
- e. Maintain the supply voltage to be $\pm 2\%$ of the EUT's rated voltage and also the frequency to be $50\text{Hz} \pm 0.5\%$.
- f. Connects the EUT's power source to the mains power supplied by the test instrument.
- g. Operating the EUT as required and measuring the voltage fluctuation and flickers of EUT's power source.
- h. Verify the fluctuations of the test supply voltage to be less than 0.4 before and after the test.

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5.4 Test Configurations



5.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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5.6 **Test Results**

Test Mode Mode 1 **Tester** Jeff **Temperature** 22°C **Humidity** 56%RH

TEST FREQ	50 Hz			
TEST VOLTS	230 VAC	230 VAC		
TEST TIME	10 Minutes			
	EUT Data	Limit		
d(t)>3.3% (ms)	0	500		
d _c (%)	0	3.3		
d _{max} (%)	0	4		
P _{st} max	0.064	1		
P _{lt} max	0.028	0.65		

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6. Electrostatic Discharge (ESD) Immunity Test

Test Result : PASS

6.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

EN 55024

as §1.3 described

and requirement of manufacturer

Report No.: S2O-A170-1903-297

Basic Standard : EN 61000-4-2

Required Performance: TT / TR (EN 301 489)

B (EN 55024)

Test Level : 2 (Contact discharge)

3 (Air discharge)

Discharge Voltage : Contact →±2kV, ±4kV (Direct / Indirect discharge)

Air $\rightarrow \pm 2kV$, $\pm 4kV$, $\pm 8kV$ (Direct discharge)

Time Interval : 1 sec. minimum

Number of discharges: Minimum 50 times at each test point (Contact)

Minimum 20 times at each test point (Air)

Test Voltage : 230Vac/50Hz to the power adapter

Tester : Marco / Wilson

Ambient Temperature : 23°C

Relative Humidity : 45%

Atmospheric Pressure : 1016mbar

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Test Instruments 6.2

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Wanuacturer	Serial No.	Calibration Date	Due Date	
Electrostatic Generator	EM TEST	DITO/ V0537100716	May 21, 2019	May 21, 2020	
TR8	ETS.	TR8/	NCR	NCR	
shielded room	LINDGREN	15353-C	INOIX	NOIX	

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Note:

- The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.

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6.3 Test Procedures

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

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- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters above the ground reference plane in the shielded room. Also a HCP (Horizontal Coupling Plane) which was connected to the ground reference plane via a cable with a $470 \mathrm{k}\Omega$ resister located at each end was placed on the wooden table and isolated with the EUT by an insulating support 0.5mm thick. The ground reference plane shall project beyond the EUT or HCP by at least 0.5m on all sides.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room. The ground reference plane shall project beyond the EUT by at least 0.5m on all sides.
- d. Keep the EUT 1m away from all other metallic walls in the shielded room as the minimum distance.
- e. The static electricity discharges shall be applied only to those points and surfaces of the EUT which are accessible to persons during normal use. Contact discharge is the preferred test method and it is applied to the conductive surfaces of EUT and coupling planes. Air discharge shall be used where contact discharge cannot be performed and it is applied to the insulating surfaces of EUT.
- f. The discharge return cable of the generator shall be kept at a distance of at least 0.2m from the EUT whilst the discharge is being applied.
- g. The time interval between successive single discharges was at least 1 second.
- h. Select appropriate points of the EUT for contact discharge and put marks on it to indicate the tested point(s). Then start the contact discharge with the tip of the discharge electrode to touch the EUT before the discharge switch is operated.
- i. Use the round discharge tip of the discharge electrode to scan the EUT to select the points for air discharge. Then start the air discharge by approaching the discharge electrode as fast as possible to touch the EUT. After each discharge, the ESD generator shall be removed from the EUT.
- j. The indirect HCP discharge test is applied at the front edge of each HCP opposite the center point of each unit of the EUT and 0.1m from the front of the EUT. The long axis of the discharge electrode shall be in the plane of the HCP and perpendicular to its front edge during the discharge.

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k. The indirect VCP (Vertical Coupling Plane) discharge test is applied to the center of one vertical edge of the coupling plane. The VCP, of dimensions 0.5m×0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. It shall be applied with sufficient different positions such that the four faces of the EUT are completely illuminated.

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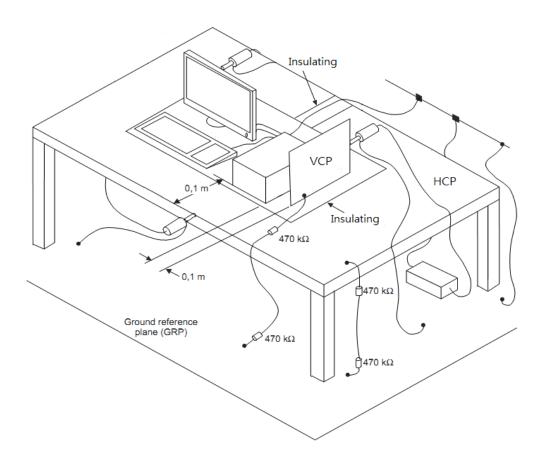
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6.4 Test Configurations



6.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

Test Results 6.6

Test Mode Mode 1

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

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Discharge		Label for	
Voltage	Type of discharge	Dischargeable	Result (Pass/Fail)
(kV)		Points	
±2	Contact	Α	Pass(1)
± 4	Contact	Α	Pass(1)
±2	Air	No dischargeable point	Pass(1)
+4	Air	4,7,9,10,13	Pass(1)
-4	Air	4,7	Pass(1)
±8	Air	1~15	Pass(1)
±2	HCP-Bottom	Edge of the HCP	Pass(1)
±2	VCP-Front	Center of the VCP	Pass(1)
±2	VCP-Left	Center of the VCP	Pass(1)
±2	VCP-Back	Center of the VCP	Pass(1)
±2	VCP-Right	Center of the VCP	Pass(1)
±4	HCP-Bottom	Edge of the HCP	Pass(1)
±4	VCP-Front	Center of the VCP	Pass(1)
±4	VCP-Left	Center of the VCP	Pass(1)
±4	VCP-Back	Center of the VCP	Pass(1)
±4	VCP-Right	Center of the VCP	Pass(1)

Observation of Performance during Test

(1) Normal operation condition specified on § 1.4 performance criteria during the test.

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Product (Generic) Standard : EN 55024

Discharge	Type of discharge	Label for Per		rmance	Pocult
Voltage (kV)		Dischargeable Points	Required	Observation	Result (Pass/Fail)
±2	Contact	A	В	A(1)	Pass
±4	Contact	Α	В	A(1)	Pass
±2	Air	No dischargeable point	В	A(1)	Pass
+4	Air	4,7,9,10,13	В	A(1)	Pass
-4	Air	4,7	В	A(1)	Pass
±8	Air	1~15	В	A(1)	Pass
±2	HCP-Bottom	Edge of the HCP	В	A(1)	Pass
±2	VCP-Front	Center of the VCP	В	A(1)	Pass
±2	VCP-Left	Center of the VCP	В	A(1)	Pass
±2	VCP-Back	Center of the VCP	В	A(1)	Pass
±2	VCP-Right	Center of the VCP	В	A(1)	Pass
±4	HCP-Bottom	Edge of the HCP	В	A(1)	Pass
±4	VCP-Front	Center of the VCP	В	A(1)	Pass
±4	VCP-Left	Center of the VCP	В	A(1)	Pass
±4	VCP-Back	Center of the VCP	В	A(1)	Pass
±4	VCP-Right	Center of the VCP	В	A(1)	Pass

Observation of Performance during Test

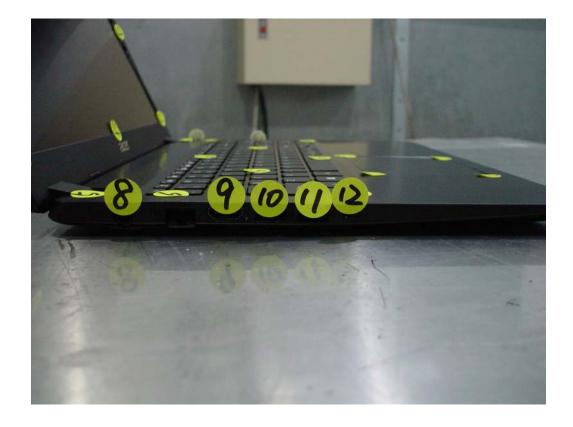
(1) Normal operation condition specified by manufacturer during the test.

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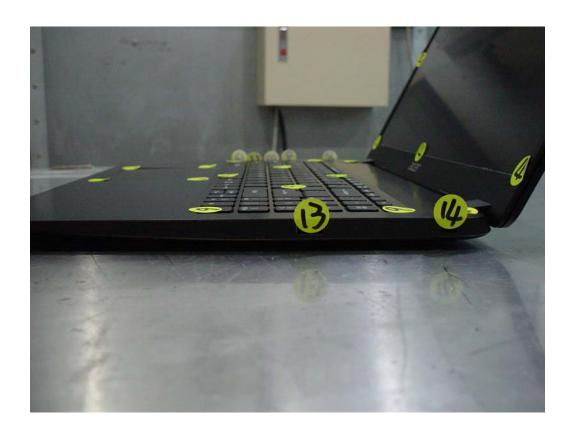
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Photographs of the Test Points on the EUT for ESD Test





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7. Radiated Electromagnetic Field (RS) Immunity Test

Test Result : PASS

7.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

Report No.: S2O-A170-1903-297

EN 55024

as §1.3 described

Basic Standard : EN 61000-4-3

Required Performance: CT / CR (EN 301 489)

A (EN 55024)

Test Level : 2

Field Strength : 3 V/m

Test Frequency Range : 80MHz ~ 6GHz (EN 301 489)

80MHz ~ 1GHz (EN 55024)

Frequency Step : 1% of the momentary frequency

Dwell Time : Minimum 3 sec. per frequency

Modulation: 1kHz Sine Wave with 80% Amplitude Modulation

Polarization of Antenna: Horizontal and Vertical

Test Voltage : 230Vac/50Hz to the power adapter

Tester : Jeff

Ambient Temperature : 23°C

Relative Humidity : 54%

Atmospheric Pressure : 1012mbar

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Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date
Signal Generator	R&S	SMB 100A / 113868	Feb. 25, 2019	Feb. 25, 2020
Dual Directional	AR	DC 6180A / 0350436	Feb. 26, 2019	Feb. 26, 2020
Coupler	AR	DC7205A / 0347145	Feb. 26, 2019	Feb. 26, 2020
Boardband	TESEQ	CBA 1G-275 / T4428	NCR	NCR
Amplifier	R&S	BBA150 / 308785	NCR	NCR
Log Antenna	R&S	HL046 / 359132/004	NCR	NCR
Stacked logPer Antenna	Schwarzbeck Mess - Elektronik	STLP 9149 / 9149-467	NCR	NCR
Isotropic E Field Probe	AR	FL7006 / 336500	Jan. 15, 2019	Jan. 15, 2020
Average Power Sensor	R&S	NRP6AN / 101001	Feb. 26, 2019	Feb. 26, 2020
Test Software	Audix	i2 / 5.16_20181108	NCR	NCR
TR3 fully-anechoic chamber	ETS. LINDGREN	TR3/ 15353-I	March 8, 2019	March 8, 2020

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Note:

- 1. The calibrations are traceable to NML/ROC.
- 2. NCR: No Calibration Required.
- 3. The calibration date of the fully-anechoic chamber listed above is the date of Field Uniformity Calibration measurement.

7.3 Test Procedures

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

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- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters and 2.0 meters away from the transmitting antenna in the fully anechoic chamber.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters and 2.0 meters away from the transmitting antenna in the fully anechoic chamber. Also if the floor-standing equipment which is capable of being stood on a non-conducting 0.8m high platform may be so arranged.
- d. All EUT's individual faces shall be fully enclosed by the "uniform area" and its wires shall be arranged parallel to the uniform area of the field.
- e. Before testing the EUT, the intensity of the established field strength is checked by placing the field sensor at a calibration grid point to give the calibrated field strength to measure the EUT.
- f. After the calibration has been verified, the test field can be generated using the values obtained from the calibration.
- g. Perform the test with the specified immunity level in the test frequency range and with the specified modulation type.
- h. The transmitting antenna is normally facing each of the four sides of the EUT with two polarizations (Vertical and Horizontal) to perform the test.
- i. The dwell time at each frequency shall be not less than the time necessary for the EUT to be exercised and be able to respond.
- The sensitive frequencies of EUT shall be analyzed separately, if any.
- k. Record the performance of the EUT.

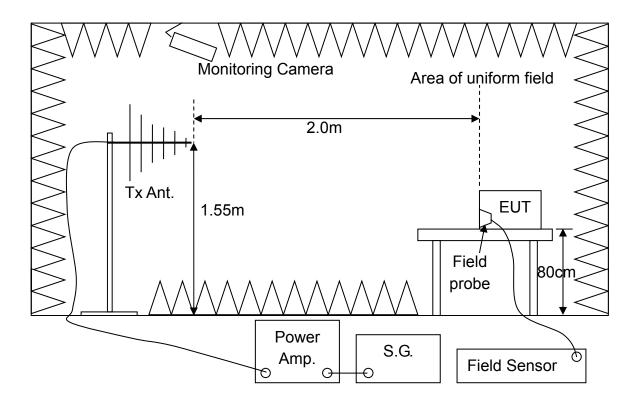
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7.4 Test Configurations



7.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

Test Results 7.6

Mode 1 **Test Mode**

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

Report No.: S2O-A170-1903-297

Те	Test Frequency Range : 80MHz ~ 6GHz				
Side of the EUT	Polarization	Result (Pass/Fail)			
Front	Н	Pass(1)			
V		Pass(1)			
Left	Н	Pass(1)			
Lon	V	Pass(1)			
Back	Н	Pass(1)			
Baok	V	Pass(1)			
Right	Н	Pass(1)			
ragin	V	Pass(1)			

Observation of Performance during Test

(1) Normal operation condition specified on § 1.4 performance criteria during the test.

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Product (Generic) Standard EN 55024

Test Frequency Range : 80MHz ~ 1GHz					
Side of the EUT	ide of the EUT Polarization Performance				
Side of the EUT	Polarization	Required Observation		(Pass/Fail)	
Front	Н	Α	A(1)	Pass	
TTOTAL	V	Α	A(1)	Pass	
Left	Н	Α	A(1)	Pass	
Lon	V	Α	A(1)	Pass	
Back	Н	Α	A(1)	Pass	
Back	V	Α	A(1)	Pass	
Right	Н	А	A(1)	Pass	
MgHt	V	А	A(1)	Pass	

Observation of Performance during Test

(1) Normal operation condition specified by manufacturer during the test.

8.

Report No.: S2O-A170-1903-297

Test Result : PASS

8.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : ETSI EN 301 489-1

Electrical fast transient / burst (EFT) Immunity Test

ETSI EN 301 489-17

EN 55024

as §1.3 described

Basic Standard : EN 61000-4-4

Required Performance : TT / TR (EN 301 489)

B (EN 55024)

Test Level : 2

Voltage Peak : ☑ ±1kV (on power supply port)

☑ ±0.5kV (on I/O signal, data and control port)

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Impulse Frequency: 5kHz

Wave Shape of the Pulse (T_r/T_h): 5ns / 50ns

Burst Duration: 15msBurst Period: 300ms

Time Duration : 1 min

Test Voltage : 230Vac/50Hz to the power adapter

Tester : Jeff
Ambient Temperature : 22°C
Relative Humidity : 56%

Atmospheric Pressure : 1013mbar

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Test Instruments 8.2

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Manufacturer	Serial No.	Calibration Date	Due Date	
EFT/Burst	EMC PARTNER	TRA2000IN6/	May 13, 2019	May 12, 2020	
Simulator	EIVIC PARTNER	870	Way 13, 2019	May 13, 2020	
Coupling	EMC PARTNER	CN-EFT1000/	Aug. 22, 2019	Aug. 22, 2020	
Clamp	EIVIC PARTNER	532	Aug. 22, 2019		
Test Software	EMC PARTNER	TEMA/	NCR	NCR	
Test Software	EIVIC PARTNER	Ver. 2.05	NCR	NCK	
TR7	ETS.	TR7/	NCR	NCR	
shielded room	LINDGREN	15353-D	NOR	NOR	

Note:

- The calibrations are traceable to NML/ROC.
- NCR: No Calibration Required. 2.

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8.3 Test Procedures

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

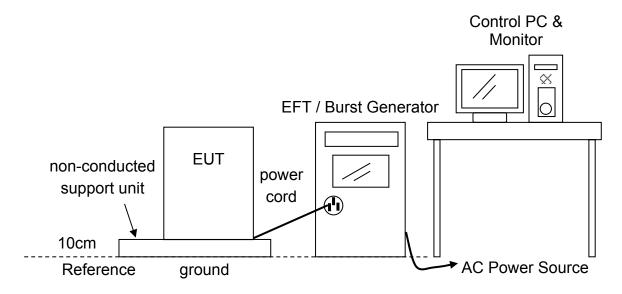
Report No.: S2O-A170-1903-297

- b. If the EUT is tabletop equipment, it was placed on a non-conducted support with a height 0.1 meters above the ground reference plane. Also the ground reference plane is placed on a wooden table with a height of 0.8 meters in the shielded room. The ground reference plane shall project beyond the EUT by at least 0.1m on all sides.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room. The ground reference plane shall project beyond the EUT by at least 0.1m on all sides.
- d. The test generator and the coupling/decoupling network shall be placed directly on, and bonded to, the ground reference plane.
- e. All cables to the EUT shall be placed on the insulation support 0.1 m above the ground reference plane. Cables not subject to electrical fast transients shall be routed as far as possible from the cable under test to minimize the coupling between the cables.
- f. Keep the EUT 0.5m away from all other conductive structures, except the ground reference plane beneath the EUT as the minimum distance. Also if any, the minimum distance between the coupling clamp and all other conductive structures, except the ground reference plane beneath the coupling clamp and EUT shall be 0.5m.
- g. Keep the length of the power and signal lines, if required, between the coupling device and the EUT to be 0.5m. If a non-detachable supply cable more than 0.5m long, the excess length of this cable shall be folded to avoid a flat coil and situated at a distance of 0,1 m above the ground reference plane.
- h. Connect the EUT's power source to the appropriate power through the coupling devices and perform the specified test level.
- i. If any, connect all the I/O signal, data and control lines between EUT and accessories/support units through the coupling devices and perform the specified test level.
- j. Record the performance of the EUT.

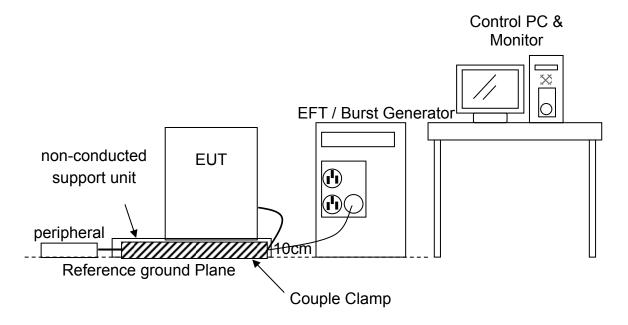
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8.4 Test Configurations

Power supply port Test



I/O signal, data and control port Test (if any)



8.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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Test Results 8.6

Test Mode Mode 1

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

Report No.: S2O-A170-1903-297

Injected Line	Voltage Peak (kV)	Injected Method	Result (Pass/Fail)
L1	±1.0	Direct	Pass(1)
L2	±1.0	Direct	Pass(1)
PE	±1.0	Direct	Pass(1)
L1 - L2 - PE	±1.0	Direct	Pass(1)
Data Line (RJ-45)	±0.5	Clamp Coupling	Pass(1)

Observation of Performance during Test

Normal operation condition specified on § 1.4 performance criteria during the (1) test.

Product (Generic) Standard : EN 55024

Injected Line	Voltage Peak	Injected	Performance		Result
Injected Line	(kV)	Method	Required	Observation	(Pass/Fail)
L1	±1.0	Direct	В	B(1)	Pass
L2	±1.0	Direct	В	B(1)	Pass
PE	±1.0	Direct	В	B(1)	Pass
L1 - L2 - PE	±1.0	Direct	В	B(1)	Pass
Data Line (RJ-45)	±0.5	Clamp Coupling	В	B(1)	Pass

Observation of Performance during Test

(1) The noise would appear from speaker of EUT while test is performing, it could self-recover after the test.

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9. Surge Immunity Test

Test Result : PASS

9.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

EN 55024

as §1.3 described

Basic Standard : EN 61000-4-5

Required Performance: TT / TR (EN 301 489)

B (EN 55024)

Test Level : ☑ 3 (line to line on power supply port)

☑ 3 (line to earth (ground) on power supply port)

Report No.: S2O-A170-1903-297

☐ 2 (on I/O signal, data and control port)

Open-circuit Test Voltage : $\boxtimes \pm 0.5$ kV, ± 1 kV (line to line on power supply port)

☑ ±0.5kV, ±1kV, ±2kV (line to earth (ground) on

power supply port)

□ ±0.5kV, ±1kV

(on I/O signal, data and control port)

CW Waveform (T_r/T_h) : 1.2 / 50µs (open-circuit voltage)

8 / 20µs (short-circuit current)

Phase Angle : 0°, 90°, 180°, 270°

Time interval : 1min. or less

Number of Test : at least 5 positive and 5 negative at selected points

Test Voltage : 230Vac/50Hz to the power adapter

Tester : Jeff
Ambient Temperature : 22°C

Ambient Temperature : 22°C Relative Humidity : 56%

Atmospheric Pressure : 1013mbar

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Test Instruments 9.2

Test Site and	Manufacturer	Model No./	Last	Calibration	
Equipment	Wanulacturer	Serial No.	Calibration Date	Due Date	
Surge	EMC PARTNER	TRA2000IN6/	Mov 12, 2010	May 13, 2020	
Simulator	EWIC PARTNER	870	May 13, 2019		
Test Software	EMC PARTNER	TEMA/	NCR	NCR	
iest Soitware	EWIC PARTNER	Ver. 2.05	NCR		
TR7	ETS.	TR7/	NCD	NCD	
shielded room	LINDGREN	15353-D	NCR	NCR	

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Note:

- 1. The calibrations are traceable to NML/ROC.
- NCR: No Calibration Required. 2.

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9.3 Test Procedures

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

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- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room.
- d. For the surge test applied to EUT's power supply and unshielded unsymmetrical interconnection lines, if required, the capacitive coupling network are used.
- e. If any, the surge test applied to the unshielded symmetrically interconnection lines of EUT, the gas arrestors coupling network are used.
- f. Keep the interconnection line, if required, or power cord between the EUT or its power source and the coupling / decoupling network to be 2m in length (or shorter).
- g. The surges have to be applied synchronized to the voltage phase at the zero-crossing and the peak value of the a.c. voltage wave (positive and negative).
- h. All lower levels including the selected test level shall be satisfied and the test voltage has to be increased by steps up to the specified test level.
- i. Connect the EUT's power source to the appropriate power through the coupling devices and perform the specified test level.
- j. If any, connect all the interconnection lines between EUT and accessories/support units through the coupling devices and perform the specified test level.
- k. Record the performance of the EUT.

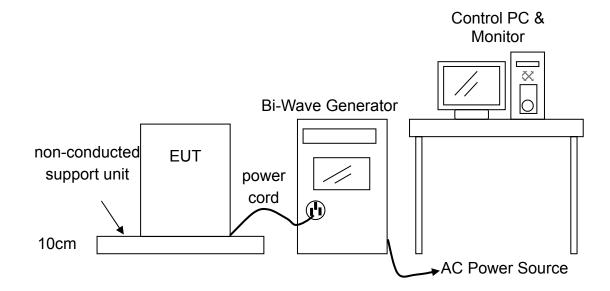
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9.4 Test Configurations



9.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

9.6 Test Results

Test Mode: Mode 1

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

Report No.: S2O-A170-1903-297

Coupled Line	Open-circuit Test Voltage	Result (Pass/Fail)			
	(kV)	0 °	90°	180°	270°
L1 - PE	±0.5	Pass(1)	Pass(1)	Pass(1)	Pass(1)
L2 - PE	±0.5	Pass(1)	Pass(1)	Pass(1)	Pass(1)
L1 - L2	±0.5	Pass(1)	Pass(1)	Pass(1)	Pass(1)
L1 - PE	±1	Pass(1)	Pass(1)	Pass(1)	Pass(1)
L2 - PE	±1	Pass(1)	Pass(1)	Pass(1)	Pass(1)
L1 - L2	±1	Pass(1)	Pass(1)	Pass(1)	Pass(1)
L1 - PE	±2	Pass(1)	Pass(1)	Pass(1)	Pass(1)
L2 - PE	±2	Pass(1)	Pass(1)	Pass(1)	Pass(1)

Observation of Performance during Test

(1) Normal operation condition specified on § 1.4 performance criteria during the test.

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Product (Generic) Standard EN 55024

	Open-circuit	Performance			Result		
Coupled Line	Test Voltage	Observation					
	(kV)	Required	0°	90°	180°	270°	(Pass/Fail)
L1 - PE	±0.5	В	A(1)	A(1)	A(1)	A(1)	Pass
L2 - PE	±0.5	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - L2	±0.5	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - PE	±1	В	A(1)	A(1)	A(1)	A(1)	Pass
L2 - PE	±1	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - L2	±1	В	A(1)	A(1)	A(1)	A(1)	Pass
L1 - PE	±2	В	A(1)	A(1)	A(1)	A(1)	Pass
L2 - PE	±2	В	A(1)	A(1)	A(1)	A(1)	Pass

Observation of Performance during Test

(1) Normal operation condition specified by manufacturer during the test.

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10. Conducted disturbances (CS) Immunity Test

Test Result : PASS

10.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

EN 55024

as §1.3 described

Basic Standard : EN 61000-4-6

Required Performance: CT / CR (EN 301 489)

A (EN 55024)

Test Level : 2

Voltage Level(e.m.f.) : 3V (e.m.f.)

Test Frequency Range : 150kHz ~ 80MHz

Frequency Step : 1% of the momentary frequency

Dwell Time : Minimum 3 sec. per frequency

Modulation : 1kHz Sine Wave with 80% Amplitude Modulation

Coupling Devices : ☑ CDN-M3 (on power supply port)

: ☐ CDN-T2 (on RJ-11 port)

☑ CDN-T4 (on LAN port)

☑ CDN-T8 (on LAN port)

☐ EM Clamp (on I/O signal, data and control port)

Report No.: S2O-A170-1903-297

Test Voltage : 230Vac/50Hz to the power adapter

Tester : Sam Huang

Ambient Temperature : 22°C **Relative Humidity** : 60%

Atmospheric Pressure : 1013mbar

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Test Site and	Ι	Model No /	Loot	Calibration	
Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date	
Signal		SML03/			
Generator	R&S	101676	July 28, 2019	July 28, 2020	
Dual Directional	AR	DC2600/	Feb. 15, 2019	Feb. 15, 2020	
Coupler	AIX	28834	1 60. 15, 2019	1 60. 15, 2020	
Power	AR	75A250/	NCR	NCR	
Amplifier		28845			
		□ FCC-801-M2-16A/ 2032	Feb. 25, 2019	Feb. 25, 2020	
	FCC	FCC-801-M3-16A/ 2060	Jan. 28, 2019	Jan. 28, 2020	
CDN		FCC-801-M5-16A/ 2020	Nov. 12, 2018	Nov. 12, 2019	
CDN		□ FCC-801-T2/ 2032	Oct. 16, 2019	Oct. 16, 2020	
	FCC	FCC-801-T4-RJ45/ 08031	Oct. 16, 2019	Oct. 16, 2020	
		□ NCDN-T8-RJ45/ 06016	Oct. 16, 2019	Oct. 16, 2020	
ATTENUATOR	BIRD	300-A-MFN-06/ 37	Oct. 21, 2019	Oct. 21, 2020	
EM CLAMP	TESEQ	KEMZ 801A / 38676	Oct. 15, 2019	Oct. 15, 2020	
Dual Channel Power Meter	R&S	NRVD/ 839374/012	Nov. 13, 2018	Nov. 13, 2019	
Dower Concer	R&S	URV5-Z2/ 835640/013	Jan. 24, 2019	Jan. 24, 2020	
Power Sensor	R&S	URV5-Z2/ 100731	Jan. 24, 2019	Jan. 24, 2020	
Test Software	Audix	i2 / 5.16_20181108	NCR	NCR	
TR4 shielded room	ETS LINDGREN	TR4/ 15353-E	NCR	NCR	

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Note:

The calibrations are traceable to NML/ROC. 1.

NCR: No Calibration Required. 2.

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10.3 Test Procedures

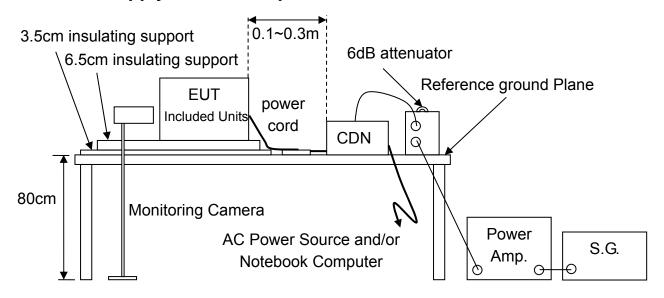
- a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.
- b. If the EUT is tabletop equipment, it was placed on a non-conducted support with a height 0.1 meters above the ground reference plane. Also the ground reference plane is placed on a wooden table with a height of 0.8 meters in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room.
- d. Decide the injection methods and test points according to the relative standard.
- e. All relevant cables shall be provide with the appropriate coupling and decoupling devices at a distance between 0.1m and 0.3m from the projected geometry of the EUT on the ground reference plane.
- f. All cables connected to each Auxiliary Equipment (AE), other than those being connected to the EUT, shall not be bundled nor wrapped and shall be kept between 30mm and 50mm above the ground reference plane.
- g. The test shall be performed with the test generator connected to each of the coupling and decoupling devices in turn while the other non-excited RF input ports of the coupling devices are terminated by a 50Ω load resistor.
- h. Perform the test with the specified immunity level in the test frequency range and with the specified modulation type.
- i. The dwell time at each frequency shall be not less than the time necessary for the EUT to be exercised and be able to respond.
- j. The sensitive frequencies of EUT and harmonics or frequencies of dominant interest shall be analyzed separately, if any.
- k. Record the performance of the EUT.

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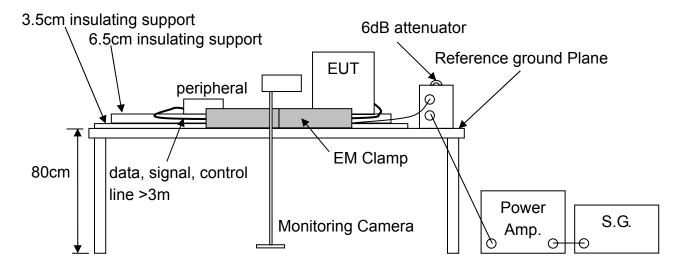
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10.4 Test Configurations

Power supply and/or LAN port Test



I/O signal, data and control port Test (if any)



10.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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10.6 Test Results

Test Mode Mode 1

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

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Injected Line	Coupling Devices	Result (Pass/Fail)
Power Lines	CDN-M3	Pass(1)
Data Lines (RJ-45)	CDN-T4 (10Mbps)	Pass(1)
	CDN-T4 (100Mbps)	Pass(1)
(1.15 16)	CDN-T8 (1Gbps)	Pass(1)

Observation of Performance during Test

(1) Normal operation condition specified on § 1.4 performance criteria during the test.

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Product (Generic) Standard : EN 55024

Injected Line	Coupling Davisos	Perfo	Result	
Injected Line	Coupling Devices	Required	Observation	(Pass/Fail)
Power Lines	CDN-M3	А	A(1)	Pass
	CDN-T4 (10Mbps)	Α	A(1)	Pass
Data Lines (RJ-45)	CDN-T4 (100Mbps)	Α	A(1)	Pass
(1.00 10)	CDN-T8 (1Gbps)	Α	A(1)	Pass

Observation of Performance during Test

(1) Normal operation condition specified by manufacturer during the test.

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11. Voltage dips, short interruptions Immunity Test

Test Result : PASS

11.1 Specifications of Immunity Test Requirement

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

as §1.3 described

Basic Standard : EN 61000-4-11

Required Performance : ☑TT/TR 0% residual voltage dips with 0.5 cycle

☑TT/TR 70% residual voltage dips with 25 cycles

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☑TT/TR 0% residual voltage interruptions

with 250 cycles

Basis Test Voltage Level (U_T) : 240Vac/50Hz to the power adapter

100Vac/50Hz to the power adapter

Test Duration: Maximum 3 dips/interruptions with a sequence

Time interval : 10s minimum between each test event

Phase Angle of Abrupt Changes: 0°, 180°

Tester : Jeff

Ambient Temperature : 22°C

Relative Humidity : 56%

Atmospheric Pressure : 1013mbar

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Product (Generic) Standard : EN 55024

as §1.3 described

Basic Standard : EN 61000-4-11

Required Performance and : ☑ B for 0% residual voltage dips with 0.5 cycles

cycles

☑ C for 0% voltage interruptions with 250/300

cycles

Basis Test Voltage Level (U_T) : 240Vac/50Hz to the power adapter

100Vac/50Hz to the power adapter

Test Duration: Maximum 3 dips/interruptions with a sequence

Time interval : 10s minimum between each test event

Phase Angle of Abrupt Changes: 0°

Tester : Jeff
Ambient Temperature : 22°C
Relative Humidity : 56%

Atmospheric Pressure : 1013mbar

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Test Site and Equipment	Manufacturer	Model No./ Serial No.	Last Calibration Date	Calibration Due Date	
Voltage DIP	EMC PARTNER	TRA2000IN6/	May 13, 2019	May 13, 2020	
Tester	EWIC PARTNER	870	Way 13, 2019		
Test Software	EMC PARTNER	TEMA/	NCR	NCR	
Test Software		Ver. 2.05	NOR	INCR	
TR7	ETS.	TR7/	NCR	NCR	
shielded room	LINDGREN	15353-D	NOR	NCR	

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Note:

- 1. The calibrations are traceable to NML/ROC.
- NCR: No Calibration Required.

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11.3 Test Procedures

a. The EUT was set up per the test configuration figured in the next section of this chapter to simulate the typical usage per the user's manual.

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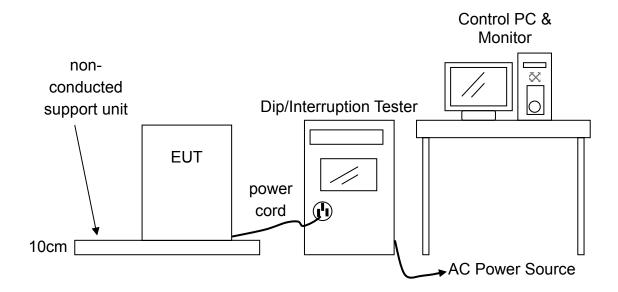
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- b. If the EUT is tabletop equipment, it was placed on a wooden table with a height 0.8 meters above the ground reference plane in the shielded room.
- c. If the EUT is floor-standing equipment, it was placed on a non-conducted support with a height of 0.1 meters above the ground reference plane in the shielded room.
- d. The test shall be performed with the EUT connected to the test Generator with the shortest power supply cable as specified by the manufacturer.
- e. If any, tests on the three-phase EUT are accomplished by using three sets of equipment mutually synchronized.
- f. During the tests, the main voltage for testing is monitored within an accuracy of 2% and the zero crossing control of the generators must have an accuracy of $\pm 10^{\circ}$.
- g. The EUT shall be tested for each selected combination of test level and duration with a sequence of three dips/interruptions with intervals of 10 sec. minimum (between each test event). Each representative mode of operation shall be test.
- h. Abrupt changes in supply voltage shall occur at zero crossings of the voltage and additional angles preferably selected from 0°, 45°, 90°, 135°, 180°, 225°, 270°, 315° on each phase.
- i. Connect the EUT's power source to the appropriate power through the test generator and perform the specified test level.
- Record the performance of the EUT.

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11.4 Test Configurations



11.5 Photographs of the Test Configurations

Please refer to the Attachment 1 of the present report.

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11.6 Test Results

Test Mode : Mode 1

Product (Generic) Standard : ETSI EN 301 489-1

ETSI EN 301 489-17

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Test Voltage: 240Vac/50Hz to the power adapter

Voltage Dips Test

Test level (% residual voltage)	Reduction Voltage (%)	Duration (cycle)	Result (Pass/Fail)
0	100	0.5	Pass(1)
0	100	1	Pass(1)
70	30	25	Pass(1)

Voltage Interruption Test

Test level	Reduction Voltage	Duration	Result (Pass/Fail)
(% residual voltage)	(%)	(cycle)	
0	100	250	Pass(1)

Observation of Performance during Test

(1) Normal operation condition specified on § 1.4 performance criteria during the test.

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Test Voltage: 100Vac/50Hz to the power adapter

Voltage Dips Test

Test level (% residual voltage)	Reduction Voltage (%)	Duration (cycle)	Result (Pass/Fail)
0	100	0.5	Pass(1)
0	100	1	Pass(1)
70	30	25	Pass(1)

Voltage Interruption Test

Test level	Reduction Voltage	Duration	Result (Pass/Fail)
(% residual voltage)	(%)	(cycle)	
0	100	250	Pass(1)

Observation of Performance during Test

(1) Normal operation condition specified on § 1.4 performance criteria during the test.

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Product (Generic) Standard : EN 55024

Test Voltage: 240Vac/50Hz to the power adapter

Voltage Dips Test

Test level	Reduction	Reduction Duration		Performance		
(% residual voltage)	Voltage (%)	(cycle)	Required	Observation	Result (Pass/Fail)	
0	>95	0.5	В	A(1)	Pass	
70	30	25	С	A(1)	Pass	

Voltage Interruption Test

Test level	Reduction	Duration	Perfo	Result	
(% residual voltage)	Voltage (%)	(cycle)	Required	Observation	
0	>95	250	С	B(2)	Pass

Observation of Performance during Test

- (1) Normal operation condition specified by manufacturer during the test.
- (2) The power adapter connected to the EUT would function off while test is performed, it could self-recover after the test.

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Test Voltage: 100Vac/50Hz to the power adapter

Voltage Dips Test

Test level	Reduction Duration		Perfo	Result	
(% residual voltage)	Voltage (%)	(cycle)	Required	Observation	
0	>95	0.5	В	B(2)	Pass
70	30	25	С	A(1)	Pass

Voltage Interruption Test

Test level	Reduction Duration		Perfo	Result	
(% residual voltage)	Voltage (%)	(cycle)	Required	Observation	
0	>95	250	С	B(2)	Pass

Observation of Performance during Test

- (1) Normal operation condition specified by manufacturer during the test.
- (2) The power adapter connected to the EUT would function off while test is performed, it could self-recover after the test.

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Attachment 1 Photographs of the Test Configurations

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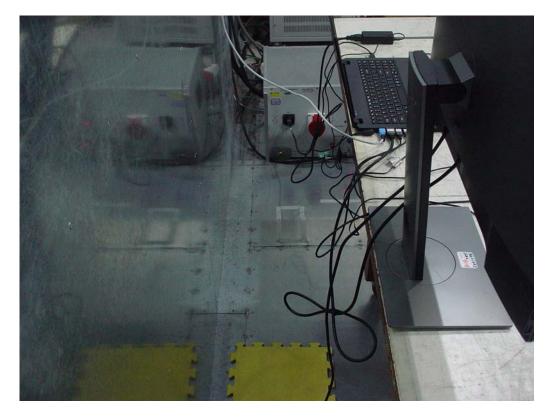
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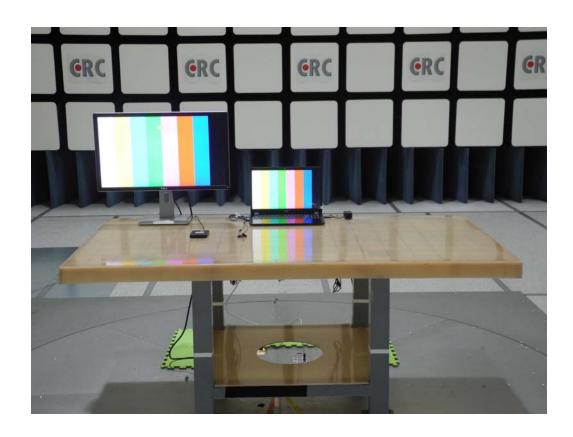
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2.	Radiated Emission Measurement	. 2
3.	Harmonic Current & Voltage Fluctuations Emission Measurement	. 3
4.	Electrostatic Discharge (ESD) Immunity Test	. 4
5.	Radiated Electromagnetic Field (RS) Immunity Test	. 4
6.	Electrical fast transient / burst (EFT) Immunity Test	. 5
7.	Surge Immunity Test	. 6
8.	Conducted disturbances (CS) Immunity Test	. 7
9.	Voltage dips. short interruptions Immunity Test	. 9

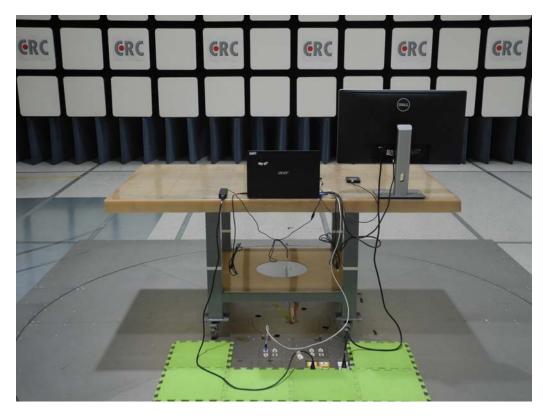
1. Conducted Emission Measurement





2. Radiated Emission Measurement





3. Harmonic Current & Voltage Fluctuations Emission Measurement





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4. Electrostatic Discharge (ESD) Immunity Test

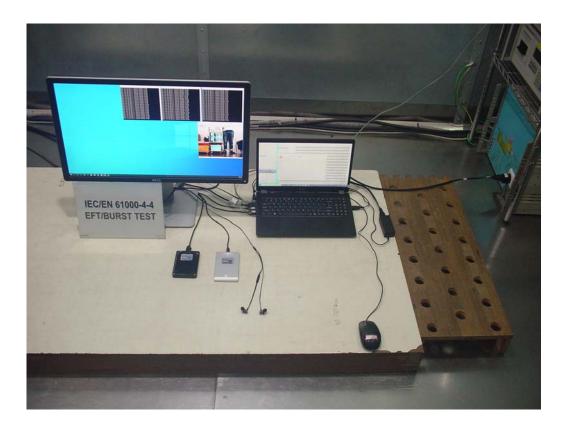


5. Radiated Electromagnetic Field (RS) Immunity Test

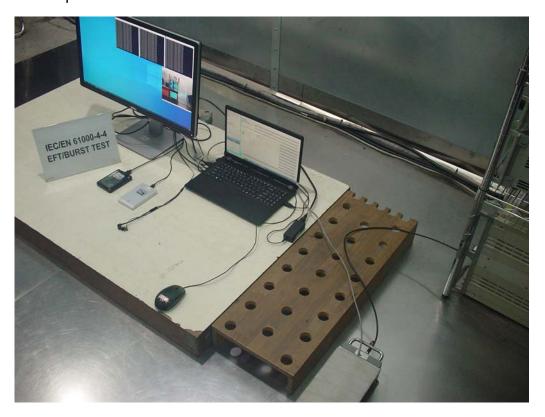


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6. Electrical fast transient / burst (EFT) Immunity Test



Test for LAN port



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7. Surge Immunity Test



8. Conducted disturbances (CS) Immunity Test



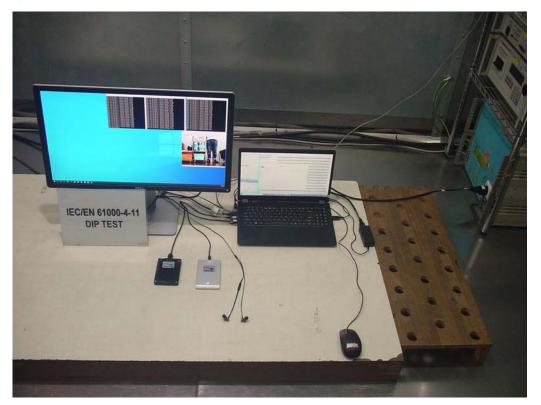


Test for LAN port





9. Voltage dips, short interruptions Immunity Test

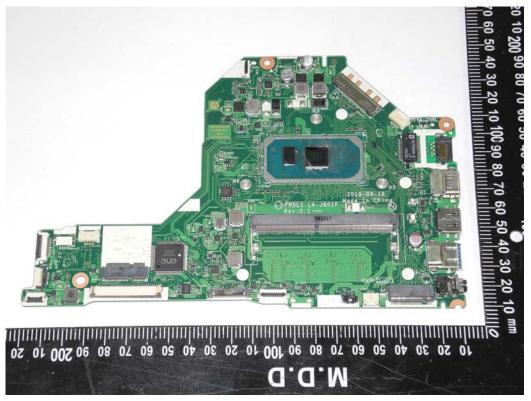


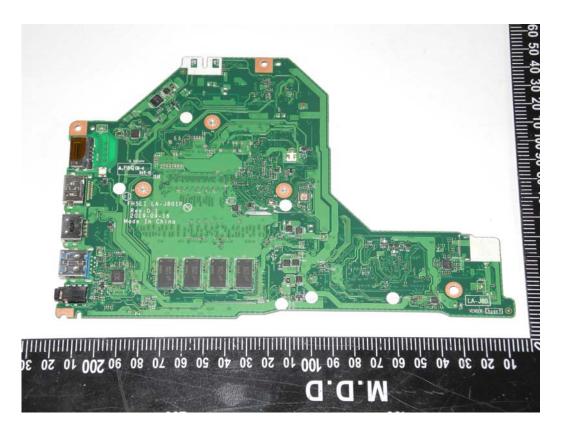
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Attachment 2 Photographs of Production (Adding Device Supplied by Customer)

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